
Keysight D9050PCIC PCIe Gen5 Compliance Application

Notices

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In This Book

This book is your guide to programming the Keysight Technologies D9050PCIC PCIe Gen5 Compliance Application.

- **Chapter 1**, “Introduction to Programming,” starting on page 7, describes compliance application programming basics.
- **Chapter 2**, “Configuration Variables and Values,” starting on page 9, **Chapter 3**, “Test Names and IDs,” starting on page 39, **Chapter 4**, “Instruments,” starting on page 91, and **Chapter 5**, “Message IDs,” starting on page 93 provide information specific to programming the D9050PCIC PCIe Gen5 Compliance Application.

How to Use This Book

Programmers who are new to compliance application programming should read all of the chapters in order. Programmers who are already familiar with this may review chapters 2, 3, 4, and 5 for changes.

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1 Introduction to Programming

Remote Programming Toolkit / 8

This chapter introduces the basics for remote programming a compliance/test application. The programming commands provide the means of remote control. Basic operations that you can do remotely with a computer and a compliance/test app running on an oscilloscope include:

- Launching and closing the application.
- Configuring the options.
- Running tests.
- Getting results.
- Controlling when and where dialogs get displayed
- Saving and loading projects.

You can accomplish other tasks by combining these functions.

Remote Programming Toolkit

The majority of remote interface features are common across all the Keysight Technologies, Inc. family of compliance/test applications. Information on those features is provided in the N5452A Compliance Application Remote Programming Toolkit available for download from Keysight here: www.keysight.com/find/rpi. The D9050PCIC PCIe Gen5 Compliance Application uses Remote Interface Revision 7.120. The help files provided with the toolkit indicate which features are supported in this version.

In the toolkit, various documents refer to "application-specific configuration variables, test information, and instrument information". These are provided in Chapters 2, 3, and 4 of this document, and are also available directly from the application's user interface when the remote interface is enabled (View>Preferences::Remote tab::Show remote interface hints). See the toolkit for more information.

2 Configuration Variables and Values

The following table contains a description of each of the D9050PCIC PCIe Gen5 Compliance Application options that you may query or set remotely using the appropriate remote interface method. The columns contain this information:

- GUI Location – Describes which graphical user interface tab contains the control used to change the value.
- Label – Describes which graphical user interface control is used to change the value.
- Variable – The name to use with the SetConfig method.
- Values – The values to use with the SetConfig method.
- Description – The purpose or function of the variable.

For example, if the graphical user interface contains this control on the **Set Up** tab:

- Enable Advanced Features

then you would expect to see something like this in the table below:

Table 1 Example Configuration Variables and Values

GUI Location	Label	Variable	Values	Description
Set Up	Enable Advanced Features	EnableAdvanced	True, False	Enables a set of optional features.

and you would set the variable remotely using:

ARSL syntax

```
arsl -a ipaddress -c "SetConfig 'EnableAdvanced' 'True'"
```

C# syntax

```
-----
remoteAte.SetConfig("EnableAdvanced", "True");
```

Here are the actual configuration variables and values used by this application:

NOTE

Some of the values presented in the table below may not be available in certain configurations. Always perform a "test run" of your remote script using the application's graphical user interface to ensure the combinations of values in your program are valid.

NOTE

The file, "ConfigInfo.txt", which may be found in the same directory as this help file, contains all of the information found in the table below in a format suitable for parsing.

Table 2 Configuration Variables and Values

GUI Location	Label	Variable	Values	Description
Configure	Bandwidth Setup for PAM4	BandwidthFilterPAM4_64G	BESSEL4	This is the setup for PAM4's bandwidth setting.
Configure	CTLE Equalization Method	CTLEEqualizationMethod_32G	SigTest, Infiniium	Specify the CTLE equalization method to use for 32GT/s Base Transmitter Tests (Jitter Tests only). By default, SigTest method is used to measure CTLE equalization.
Configure	CTLE Equalization Method	CTLEEqualizationMethod_64G	SigTest, Infiniium	Specify the CTLE equalization method to use for 64GT/s Base Transmitter Tests (Jitter Tests only). By default, Infiniium method is used to measure CTLE equalization.
Configure	Clock Recovery Method	ClockRecoveryMethod_64G	PCIe6CXLBehavioralSRIS, SecondOrderPLLOJTF	This is the setting to enable user to select clock recovery method in 64GT/s.
Configure	Compliance Signal Check	EnableSignalCheck_16G	1.0, 0.0	When signal check is enabled, the input signal is pre-tested and verified to be within a reasonable range of timing and voltage limits. This can be useful for detecting problems like cabling errors before a test is run.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Compliance Signal Check	EnableSignalCheck_2P5G	1.0, 0.0	When signal check is enabled, the input signal is pre-tested and verified to be within a reasonable range of timing and voltage limits. This can be useful for detecting problems like cabling errors before a test is run.
Configure	Compliance Signal Check	EnableSignalCheck_32G	1.0, 0.0	When signal check is enabled, the input signal is pre-tested and verified to be within a reasonable range of timing and voltage limits. This can be useful for detecting problems like cabling errors before a test is run.
Configure	Compliance Signal Check	EnableSignalCheck_5G	1.0, 0.0	When signal check is enabled, the input signal is pre-tested and verified to be within a reasonable range of timing and voltage limits. This can be useful for detecting problems like cabling errors before a test is run.
Configure	Compliance Signal Check	EnableSignalCheck_8G	1.0, 0.0	When signal check is enabled, the input signal is pre-tested and verified to be within a reasonable range of timing and voltage limits. This can be useful for detecting problems like cabling errors before a test is run.
Configure	Gen 2 Ref Clock Transfer Function (Common Clock)	Gen2CommonRefClkTF	H1: 5MHz, 1.0dB peaking H2: 16MHz, 3.0dB peaking, H1: 8MHz, 3.0dB peaking H2: 16MHz, 3.0dB peaking	Select the transfer function for Gen 2 reference clock signal.
Configure	Linear Fit Pulse Delay, Dp	LinearFitPulseDelay_64G	(Accepts user-defined text), 4	This is the setting for linear fit pulse delay.
Configure	Linear Fit Pulse Length, Np	LinearFitPulseLength_64G	(Accepts user-defined text), 600	This is the setting for linear fit pulse length.
Configure	Low Pass Filter	EnableLowPassFilter	1, 0	This configuration will enable low pass filter option for PCIe-SIG Clock Jitter Tools. When this is enabled, an additional low pass filter will be enabled.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Manual Input Pattern File	ManuallInputPatternFile_64G	Disabled, Enabled	This is the setting to enable user to manually input the pattern file.
Configure	Manual Input Scope Random Noise	ManuallInputScopeRNValue_64G	Disabled, Enabled	This is the setting to enable user to manually input the scope random noise values.
Configure	Noise Floor Deembed	EnableNFDeembed	1, 0	This configuration will enable noise floor deembedding for PCIe-SIG Clock Jitter Tools. When this is enabled, the noise floor waveform will be analyzed to remove the phase jitter impacts from the test environment.
Configure	Noise Reduction BW, Hz	EBW_16G_BASE	(Accepts user-defined text), 50.0E+9, 25.0E+9, 20.0E+9, 16.0E+9	Specify the noise reduction bandwidth to use for all 16GT/s Base Transmitter Tests. The acceptable range of bandwidth is from 16.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_16G_EP	(Accepts user-defined text), 50.0E+9, 25.0E+9, 20.0E+9, 16.0E+9	Specify the noise reduction bandwidth to use for all 16GT/s CEM End Point Tests. The acceptable range of bandwidth is from 16.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_16G_RC	(Accepts user-defined text), 50.0E+9, 25.0E+9, 20.0E+9, 16.0E+9	Specify the noise reduction bandwidth to use for all 16GT/s CEM Root Complex Tests. The acceptable range of bandwidth is from 16.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_2P5G_BASE	(Accepts user-defined text), 13.0E+9, 12.5E+9, 12.0E+9, 10.0E+9, 8.0E+9, 7.0E+9, 6.5E+9, 6.0E+9	Specify the noise reduction bandwidth to use for all tests. The acceptable range of bandwidth is from 2.5GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_2P5G_EP	(Accepts user-defined text), 13.0E+9, 12.5E+9, 12.0E+9, 10.0E+9, 8.0E+9, 7.0E+9, 6.5E+9, 6.0E+9	Specify the noise reduction bandwidth to use for all tests. The acceptable range of bandwidth is from 2.5GHz to 63.0Hz.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Noise Reduction BW, Hz	EBW_2P5G_RC	(Accepts user-defined text), 13.0E+9, 12.5E+9, 12.0E+9, 10.0E+9, 8.0E+9, 7.0E+9, 6.5E+9, 6.0E+9	Specify the noise reduction bandwidth to use for all tests. The acceptable range of bandwidth is from 2.5GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_32G_BASE	(Accepts user-defined text), 50.0E+9, 33.0E+9	Specify the noise reduction bandwidth to use for all 32GT/s Base Transmitter Tests. The acceptable range of bandwidth is from 32.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_32G_EP	(Accepts user-defined text), 50.0E+9, 33.0E+9	Specify the noise reduction bandwidth to use for all 32GT/s CEM End Point Tests. The acceptable range of bandwidth is from 32.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_32G_RC	(Accepts user-defined text), 50.0E+9, 33.0E+9	Specify the noise reduction bandwidth to use for all 32GT/s CEM Root Complex Tests. The acceptable range of bandwidth is from 32.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_5G_BASE	(Accepts user-defined text), 13.0E+9, 12.5E+9, 12.0E+9, 10.0E+9, 8.0E+9	Specify the noise reduction bandwidth to use for all tests. The acceptable range of bandwidth is from 5.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_5G_EP	(Accepts user-defined text), 13.0E+9, 12.5E+9, 12.0E+9, 10.0E+9, 8.0E+9	Specify the noise reduction bandwidth to use for all tests. The acceptable range of bandwidth is from 5.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_5G_RC	(Accepts user-defined text), 13.0E+9, 12.5E+9, 12.0E+9, 10.0E+9, 8.0E+9	Specify the noise reduction bandwidth to use for all tests. The acceptable range of bandwidth is from 5.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_64G_BASE	(Accepts user-defined text), 33.0E+9	Specify the noise reduction bandwidth to use for all 64GT/s Base Transmitter Tests. The acceptable range of bandwidth is from 32.0GHz to 63.0Hz. Note: This bandwidth setting is set on the applied filter response.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Noise Reduction BW, Hz	EBW_8G_BASE	(Accepts user-defined text), 13.0E+9, 12.5E+9, 12.0E+9, 10.0E+9	Specify the noise reduction bandwidth to use for all tests. The acceptable range of bandwidth is from 8.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_8G_EP	(Accepts user-defined text), 13.0E+9, 12.5E+9, 12.0E+9, 10.0E+9	Specify the noise reduction bandwidth to use for all tests. The acceptable range of bandwidth is from 8.0GHz to 63.0Hz.
Configure	Noise Reduction BW, Hz	EBW_8G_RC	(Accepts user-defined text), 13.0E+9, 12.5E+9, 12.0E+9, 10.0E+9	Specify the noise reduction bandwidth to use for all tests. The acceptable range of bandwidth is from 8.0GHz to 63.0Hz.
Configure	Number of UI	NumUI_16G	(Accepts user-defined text), 8.0E+6, 2.5E+6, 2.0E+6, 1.6E+6, 1.0E+6, 500.0E+3, 250.0E+3	This is the minimum number of unit intervals used in the Eye-Width, TJ at BER-12, Maximum DJ , RMS RJ and Template tests. These measurements should be made using the compliance pattern at a sample size of at least 1E+6 (1,000,000) UI as specified in the PCI Express CEM Specification Rev. 2.0. Specifying a greater number of UI will increase the test time and accuracy of the tests.
Configure	Number of UI	NumUI_2P5G	(Accepts user-defined text), 1.6E+6, 1.0E+6, 500.0E+3, 250.0E+3	This is the minimum number of unit intervals used in the Eye-Width, TJ at BER-12, Maximum DJ , RMS RJ and Template tests. These measurements should be made using the compliance pattern at a sample size of at least 1E+6 (1,000,000) UI as specified in the PCI Express CEM Specification Rev. 2.0. Specifying a greater number of UI will increase the test time and accuracy of the tests.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Number of UI	NumUI_32G	(Accepts user-defined text), 8.0E+6, 2.5E+6, 2.0E+6, 1.6E+6	This is the minimum number of unit intervals used in the Eye-Width, TJ at BER-12, Maximum DJ , RMS RJ and Template tests. These measurements should be made using the compliance pattern at a sample size of at least 1E+6 (1,000,000) UI as specified in the PCI Express CEM Specification Rev. 2.0. Specifying a greater number of UI will increase the test time and accuracy of the tests.
Configure	Number of UI	NumUI_5G	(Accepts user-defined text), 1.6E+6, 1.0E+6, 500.0E+3, 250.0E+3	This is the minimum number of unit intervals used in the Eye-Width, TJ at BER-12, Maximum DJ , RMS RJ and Template tests. These measurements should be made using the compliance pattern at a sample size of at least 1E+6 (1,000,000) UI as specified in the PCI Express CEM Specification Rev. 2.0. Specifying a greater number of UI will increase the test time and accuracy of the tests.
Configure	Number of UI	NumUI_64G	(Accepts user-defined text), 4.5E+6, 2.0E+6	This is the minimum number of unit intervals used in the Eye-Width, TJ at BER-12, Maximum DJ , RMS RJ and Template tests. These measurements should be made using the compliance pattern at a sample size of at least 1E+6 (1,000,000) UI as specified in the PCI Express CEM Specification Rev. 2.0. Specifying a greater number of UI will increase the test time and accuracy of the tests.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Number of UI	NumUI_8G	(Accepts user-defined text), 2.4E+6, 1.6E+6, 1.0E+6, 500.0E+3, 250.0E+3	This is the minimum number of unit intervals used in the Eye-Width, TJ at BER-12, Maximum DJ , RMS RJ and Template tests. These measurements should be made using the compliance pattern at a sample size of at least 1E+6 (1,000,000) UI as specified in the PCI Express CEM Specification Rev. 2.0. Specifying a greater number of UI will increase the test time and accuracy of the tests.
Configure	Number of UI	NumUI_RefClk	(Accepts user-defined text), 200000, 100000, 50000, 25000	This is the minimum number of unit intervals used in reference clock tests.
Configure	Number of UI for PWJ Tests	NumUI_PWJ_16G	(Accepts user-defined text), 2.0E+6, 1.6E+6, 1.0E+6, 500.0E+3, 250.0E+3	This is the minimum number of unit intervals used in PWJ tests. These measurements should be made using the clock pattern at a sample size of at least 1E+6 (1,000,000) UI as specified in the PCI Express CEM Specification Rev. 2.0. Specifying a greater number of UI will increase the test time and accuracy of the tests.
Configure	OJTF Damping Factor	OJTFDampingFactor_64G	(Accepts user-defined text), 0.707	This is the setting to enable user to define OJTF damping factor in 64GT/s.
Configure	OJTF Loop Bandwidth, Hz	OJTFLoopBandwidth_64G	(Accepts user-defined text), 10000000	This is the setting to enable user to define OJTF loop bandwidth (Hz) in 64GT/s.
Configure	Points per UI, M	PointsPerUI_64G	(Accepts user-defined text), 32	This is the setting for sample points per UI.
Configure	RefClk Noise Reduction BW, Hz	ClockEBW	0.0, 8.0E+9, 7.0E+9, 6.0E+9, 5.0E+9, 4.5E+9, 4.0E+9, 3.5E+9, 3.0E+9, 2.5E+9, 2.0E+9, 1.5E+9, 1.0E+9	Select the bandwidth to acquire reference clock signal.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	RefClk Settings Precedence	ReferenceClockPrecedence	Number of Clock UI Cycles, Sampling Rate	When memory depth is insufficient (Application limits to 200 Mpts), select which setting takes precedence. Number of Clock UI Cycles takes precedence means sampling rate is limited. Sampling rate takes precedence means Number of Clock UI Cycles is limited. When memory depth is sufficient, no changes are made. If "Use Real Edge Connection" is enabled, precedence will be set to Sampling Rate since Real-Edge connection sample rate of 160GSa/s has been configured.
Configure	SSC Removal	EnableSSCRemoval	1, 0	This configuration will enable SSC removal for PCIE-SIG Clock Jitter Tools. When this is enabled, SSC spikes will be removed from the phase jitter spectrum. Per the PCIe* 5.0 base spec, this feature must be enabled for PCIe* 5.0 and 4.0.
Configure	Sample Rate, GSa/s	SRate_16G	160.0E+9, 80.0E+9, 256.0E+9, 128.0E+9	(Limited availability*) Specify the sample rate to use for all PCIE 2.0 (5.0 GT/s) tests or PCIE 3.0 (8.0 GT/s) tests.
Configure	Sample Rate, GSa/s	SRate_2P5G	160.0E+9, 80.0E+9, 40.0E+9, 20.0E+9, 128.0E+9, 64.0E+9, 32.0E+9	(Limited availability*) Specify the sample rate to use for all PCIE 2.0 (5.0 GT/s) tests or PCIE 3.0 (8.0 GT/s) tests.
Configure	Sample Rate, GSa/s	SRate_32G	160.0E+9, 80.0E+9, 256.0E+9	(Limited availability*) Specify the sample rate to use for all PCIE 2.0 (5.0 GT/s) tests or PCIE 3.0 (8.0 GT/s) tests.
Configure	Sample Rate, GSa/s	SRate_5G	160.0E+9, 80.0E+9, 40.0E+9, 128.0E+9, 64.0E+9	(Limited availability*) Specify the sample rate to use for all PCIE 2.0 (5.0 GT/s) tests or PCIE 3.0 (8.0 GT/s) tests.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Sample Rate, GSa/s	SRate_64G	160.0E+9, 80.0E+9, 256.0E+9	(Limited availability [*]) Specify the sample rate to use for all PCIe 6.0 (64.0 GT/s) tests.
Configure	Sample Rate, GSa/s	SRate_8G	160.0E+9, 80.0E+9, 40.0E+9, 256.0E+9, 128.0E+9, 64.0E+9	(Limited availability [*]) Specify the sample rate to use for all PCIe 2.0 (5.0 GT/s) tests or PCIe 3.0 (8.0 GT/s) tests.
Configure	Sample Rate, GSa/s	SRate_RefClk	Maximum, 80.0E+9, 40.0E+9, 20.0E+9, 256.0E+9, 128.0E+9, 64.0E+9, 32.0E+9	Select the sample rate to acquire reference clock signal.
Configure	Show Jitter Filter Plot	ShowJitterFilterPlot	0, 2, 3, 4, 5	Select the clock jitter plot to display. Generating plots will increase test runtime.
Configure	SigTest Version	AddIn_SigTestVer16GT	(Accepts user-defined text), 4.0.52	Specify the version of the SigTest for 16.0 GT/s Add-In Card Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	AddIn_SigTestVer2P5GT	(Accepts user-defined text), 3.2.0.3	Specify the version of the SigTest for 2.5 GT/s Add-In Card Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	AddIn_SigTestVer32GT	(Accepts user-defined text), 5.1.04	Specify the version of the SigTest for 32.0 GT/s Add-In Card Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	AddIn_SigTestVer5GT	(Accepts user-defined text), 3.2.0.3	Specify the version of the SigTest for 5.0 GT/s Add-In Card Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	AddIn_SigTestVer8GT	(Accepts user-defined text), 3.2.0.3	Specify the version of the SigTest for 8.0 GT/s Add-In Card Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	Base_SigTestVer16GT	(Accepts user-defined text), 4.0.52	Specify the version of the SigTest for 16.0 GT/s Base Transmitter Tests. Setting is defined according to Data Rate.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	SigTest Version	Base_SigTestVer2P5GT	(Accepts user-defined text), 4.0.52	Specify the version of the SigTest for 2.5 GT/s Base Transmitter Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	Base_SigTestVer32GT	(Accepts user-defined text), 5.1.04	Specify the version of the SigTest for 32.0 GT/s Base Transmitter Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	Base_SigTestVer5GT	(Accepts user-defined text), 4.0.52	Specify the version of the SigTest for 5.0 GT/s Base Transmitter Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	Base_SigTestVer8GT	(Accepts user-defined text), 4.0.52	Specify the version of the SigTest for 8.0 GT/s Base Transmitter Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	Preset_SigTestVer16GT	(Accepts user-defined text), 4.0.52	Specify the version of the SigTest for 16.0 GT/s Base Transmitter Tests (Equalization Preset Test). Setting is defined according to Data Rate.
Configure	SigTest Version	Preset_SigTestVer32GT	(Accepts user-defined text), 5.1.04	Specify the version of the SigTest for 32.0 GT/s Base Transmitter Tests (Equalization Preset Test). Setting is defined according to Data Rate.
Configure	SigTest Version	Preset_SigTestVer8GT	(Accepts user-defined text), 4.0.52	Specify the version of the SigTest for 8.0 GT/s Base Transmitter Tests (Equalization Preset Test). Setting is defined according to Data Rate.
Configure	SigTest Version	System_SigTestVer16GT	(Accepts user-defined text), 4.0.52	Specify the version of the SigTest for 16.0 GT/s System Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	System_SigTestVer2P5GT	(Accepts user-defined text), 3.2.0.3	Specify the version of the SigTest for 2.5 GT/s System Tests. Setting is defined according to Data Rate.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	SigTest Version	System_SigTestVer32GT	(Accepts user-defined text), 5.1.04	Specify the version of the SigTest for 32.0 GT/s System Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	System_SigTestVer5GT	(Accepts user-defined text), 3.2.0.3	Specify the version of the SigTest for 5.0 GT/s System Tests. Setting is defined according to Data Rate.
Configure	SigTest Version	System_SigTestVer8GT	(Accepts user-defined text), 3.2.0.3	Specify the version of the SigTest for 8.0 GT/s System Tests. Setting is defined according to Data Rate.
Configure	SigTest Version (DC Calculation Method)	Preset_SigTestVer32GT_DC	(Accepts user-defined text), 4.0.52	Specify the version of the SigTest for 32.0 GT/s Base Transmitter Tests (Equalization Preset Test) with DC calculation method. Setting is defined according to Data Rate.
Configure	Sine(x)/x Interpolation	SineXInterpolation_16G	ON, OFF, INT1, INT2, INT4	Sine(x)/x Interpolation for data rate 16GT/s. If "Use Real Edge Connection" is enabled, interpolation will be set to OFF since Real-Edge connection already uses a high sample rate of 160GSa/s. Note: Interpolation shouldn't be applied to PWJ tests if Number of UI, Sample Rate and Noise Reduction BW are not set to default values as it will cause Sigstest to have memory allocation issue.
Configure	Sine(x)/x Interpolation	SineXInterpolation_2P5G	ON, OFF, INT1, INT2, INT4	Sine(x)/x Interpolation for data rate 2.5GT/s. If "Use Real Edge Connection" is enabled, interpolation will be set to OFF since Real-Edge connection already uses a high sample rate of 160GSa/s.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Sine(x)/x Interpolation	SineXInterpolation_32G	ON, OFF, INT1, INT2, INT4	Sine(x)/x Interpolation for data rate 32GT/s. If "Use Real Edge Connection" is enabled, interpolation will be set to OFF since Real-Edge connection already uses a high sample rate of 160GSa/s.
Configure	Sine(x)/x Interpolation	SineXInterpolation_5G	ON, OFF, INT1, INT2, INT4	Sine(x)/x Interpolation for data rate 5GT/s. If "Use Real Edge Connection" is enabled, interpolation will be set to OFF since Real-Edge connection already uses a high sample rate of 160GSa/s.
Configure	Sine(x)/x Interpolation	SineXInterpolation_64G	ON, OFF, INT1, INT2, INT4	Sine(x)/x Interpolation for data rate 64GT/s.
Configure	Sine(x)/x Interpolation	SineXInterpolation_64G	ON, OFF, INT1, INT2, INT4	Sine(x)/x Interpolation for data rate 64GT/s. If "Use Real Edge Connection" is enabled, interpolation will be set to OFF since Real-Edge connection already uses a high sample rate of 160GSa/s.
Configure	Sine(x)/x Interpolation	SineXInterpolation_8G	ON, OFF, INT1, INT2, INT4	Sine(x)/x Interpolation for data rate 8GT/s. If "Use Real Edge Connection" is enabled, interpolation will be set to OFF since Real-Edge connection already uses a high sample rate of 160GSa/s.
Configure	Use Real Edge Connection	UseRealEdgeConnection	Enabled, Disabled	Use the Real Edge Channels when performing tests for 32GT/s data rate. By default Real-Edge Connection will be disabled.
Configure	Voltage Test Histogram Window	VoltageHistogramWindow2 P5G_BASE	(Accepts user-defined text in Debug mode), 0.01, 0.1	Specify the histogram window from centre 0.5 UI to use for 2.5GT/s Base Transmitter Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, +-0.01 UI window from centre 0.5 UI is used.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Voltage Test Histogram Window	VoltageHistogramWindow2 P5G_EP	(Accepts user-defined text in Debug mode), 0.01, 0.1	Specify the histogram window from centre 0.5 UI to use for 2.5GT/s End Point Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, +-0.01 UI window from centre 0.5 UI is used.
Configure	Voltage Test Histogram Window	VoltageHistogramWindow2 P5G_RC	(Accepts user-defined text in Debug mode), 0.01, 0.1	Specify the histogram window from centre 0.5 UI to use for 2.5GT/s Root Complex Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, +-0.01 UI window from centre 0.5 UI is used.
Configure	Voltage Test Histogram Window	VoltageHistogramWindow5 G_BASE	(Accepts user-defined text in Debug mode), 0.01, 0.1	Specify the histogram window from centre 0.5 UI to use for 5GT/s Base Transmitter Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, +-0.01 UI window from centre 0.5 UI is used.
Configure	Voltage Test Histogram Window	VoltageHistogramWindow5 G_EP	(Accepts user-defined text in Debug mode), 0.01, 0.1	Specify the histogram window from centre 0.5 UI to use for 5GT/s End Point Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, +-0.01 UI window from centre 0.5 UI is used.
Configure	Voltage Test Histogram Window	VoltageHistogramWindow5 G_RC	(Accepts user-defined text in Debug mode), 0.01, 0.1	Specify the histogram window from centre 0.5 UI to use for 5GT/s Root Complex Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, +-0.01 UI window from centre 0.5 UI is used.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Voltage Test Interpolation Ratio	VoltageInterpolationRatio2P5G_BASE	OFF, INT2, INT4	Specify the interpolation ratio during load waveform to use for 2.5GT/s Base Transmitter Tests (Deemphasized Voltage Ratio and Peak Differential Output Voltage Test only). By default, interpolation ratio of 4 is used.
Configure	Voltage Test Interpolation Ratio	VoltageInterpolationRatio2P5G_EP	OFF, INT2, INT4	Specify the interpolation ratio during load waveform to use for 2.5GT/s End Point Tests (Deemphasized Voltage Ratio and Peak Differential Output Voltage Test only). By default, interpolation ratio of 4 is used.
Configure	Voltage Test Interpolation Ratio	VoltageInterpolationRatio2P5G_RC	OFF, INT2, INT4	Specify the interpolation ratio during load waveform to use for 2.5GT/s Root Complex Tests (Deemphasized Voltage Ratio and Peak Differential Output Voltage Test only). By default, interpolation ratio of 4 is used.
Configure	Voltage Test Interpolation Ratio	VoltageInterpolationRatio5G_BASE	OFF, INT2, INT4	Specify the interpolation ratio during load waveform to use for 5GT/s Base Transmitter Tests (Deemphasized Voltage Ratio and Peak Differential Output Voltage Test only). By default, interpolation ratio of 4 is used.
Configure	Voltage Test Interpolation Ratio	VoltageInterpolationRatio5G_EP	OFF, INT2, INT4	Specify the interpolation ratio during load waveform to use for 5GT/s End Point Tests (Deemphasized Voltage Ratio and Peak Differential Output Voltage Test only). By default, interpolation ratio of 4 is used.
Configure	Voltage Test Interpolation Ratio	VoltageInterpolationRatio5G_RC	OFF, INT2, INT4	Specify the interpolation ratio during load waveform to use for 5GT/s Root Complex Tests (Deemphasized Voltage Ratio and Peak Differential Output Voltage Test only). By default, interpolation ratio of 4 is used.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Voltage Test Measurement Method	VoltageMeasurementMethod2P5G_BASE	SigTest, Infiniium	Specify the measurement method to use for 2.5GT/s Base Transmitter Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, SigTest is used for the measurement.
Configure	Voltage Test Measurement Method	VoltageMeasurementMethod2P5G_EP	SigTest, Infiniium	Specify the measurement method to use for 2.5GT/s CEM End Point Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, SigTest is used for the measurement.
Configure	Voltage Test Measurement Method	VoltageMeasurementMethod2P5G_RC	SigTest, Infiniium	Specify the measurement method to use for 2.5GT/s CEM Root Complex Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, SigTest is used for the measurement.
Configure	Voltage Test Measurement Method	VoltageMeasurementMethod5G_BASE	SigTest, Infiniium	Specify the measurement method to use for 5GT/s Base Transmitter Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, SigTest is used for the measurement.
Configure	Voltage Test Measurement Method	VoltageMeasurementMethod5G_EP	SigTest, Infiniium	Specify the measurement method to use for 5GT/s CEM End Point Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, SigTest is used for the measurement.
Configure	Voltage Test Measurement Method	VoltageMeasurementMethod5G_RC	SigTest, Infiniium	Specify the measurement method to use for 5GT/s CEM Root Complex Tests (Deemphasized Voltage Ratio Test and Peak Differential Output Voltage Test only). By default, SigTest is used for the measurement.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Run Tests	Event	RunEvent	(None), Fail, Margin < N, Pass	Names of events that can be used with the StoreMode=Event or RunUntil RunEventAction options
Run Tests	RunEvent=Margin < N: Minimum required margin %	RunEvent_Margin < N_MinPercent	Any integer in range: 0 <= value <= 99	Specify N using the 'Minimum required margin %' control.
Set Up	16GT/s Preset P0	16G P00	0.0, 1.0	Enable 16GT/s Preset P0.
Set Up	16GT/s Preset P1	16G P01	0.0, 1.0	Enable 16GT/s Preset P1.
Set Up	16GT/s Preset P10	16G P10	0.0, 1.0	Enable 16GT/s Preset P10.
Set Up	16GT/s Preset P2	16G P02	0.0, 1.0	Enable 16GT/s Preset P2.
Set Up	16GT/s Preset P3	16G P03	0.0, 1.0	Enable 16GT/s Preset P3.
Set Up	16GT/s Preset P4	16G P04	0.0, 1.0	Enable 16GT/s Preset P4.
Set Up	16GT/s Preset P5	16G P05	0.0, 1.0	Enable 16GT/s Preset P5.
Set Up	16GT/s Preset P6	16G P06	0.0, 1.0	Enable 16GT/s Preset P6.
Set Up	16GT/s Preset P7	16G P07	0.0, 1.0	Enable 16GT/s Preset P7.
Set Up	16GT/s Preset P8	16G P08	0.0, 1.0	Enable 16GT/s Preset P8.
Set Up	16GT/s Preset P9	16G P09	0.0, 1.0	Enable 16GT/s Preset P9.
Set Up	32GT/s Preset P0	32G P00	0.0, 1.0	Enable 32GT/s Preset P0.
Set Up	32GT/s Preset P1	32G P01	0.0, 1.0	Enable 32GT/s Preset P1.
Set Up	32GT/s Preset P10	32G P10	0.0, 1.0	Enable 32GT/s Preset P10.
Set Up	32GT/s Preset P2	32G P02	0.0, 1.0	Enable 32GT/s Preset P2.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	32GT/s Preset P3	32G P03	0.0, 1.0	Enable 32GT/s Preset P3.
Set Up	32GT/s Preset P4	32G P04	0.0, 1.0	Enable 32GT/s Preset P4.
Set Up	32GT/s Preset P5	32G P05	0.0, 1.0	Enable 32GT/s Preset P5.
Set Up	32GT/s Preset P6	32G P06	0.0, 1.0	Enable 32GT/s Preset P6.
Set Up	32GT/s Preset P7	32G P07	0.0, 1.0	Enable 32GT/s Preset P7.
Set Up	32GT/s Preset P8	32G P08	0.0, 1.0	Enable 32GT/s Preset P8.
Set Up	32GT/s Preset P9	32G P09	0.0, 1.0	Enable 32GT/s Preset P9.
Set Up	64GT/s Preset P0	64G Q00	0.0, 1.0	Enable 64GT/s Preset P0.
Set Up	64GT/s Preset P1	64G Q01	0.0, 1.0	Enable 64GT/s Preset P1.
Set Up	64GT/s Preset P10	64G Q10	0.0, 1.0	Enable 64GT/s Preset P10.
Set Up	64GT/s Preset P2	64G Q02	0.0, 1.0	Enable 64GT/s Preset P2.
Set Up	64GT/s Preset P3	64G Q03	0.0, 1.0	Enable 64GT/s Preset P3.
Set Up	64GT/s Preset P4	64G Q04	0.0, 1.0	Enable 64GT/s Preset P4.
Set Up	64GT/s Preset P5	64G Q05	0.0, 1.0	Enable 64GT/s Preset P5.
Set Up	64GT/s Preset P6	64G Q06	0.0, 1.0	Enable 64GT/s Preset P6.
Set Up	64GT/s Preset P7	64G Q07	0.0, 1.0	Enable 64GT/s Preset P7.
Set Up	64GT/s Preset P8	64G Q08	0.0, 1.0	Enable 64GT/s Preset P8.
Set Up	64GT/s Preset P9	64G Q09	0.0, 1.0	Enable 64GT/s Preset P9.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	8GT/s Preset P0	8G P00	0.0, 1.0	Enable 8GT/s Preset P0.
Set Up	8GT/s Preset P1	8G P01	0.0, 1.0	Enable 8GT/s Preset P1.
Set Up	8GT/s Preset P10	8G P10	0.0, 1.0	Enable 8GT/s Preset P10.
Set Up	8GT/s Preset P2	8G P02	0.0, 1.0	Enable 8GT/s Preset P2.
Set Up	8GT/s Preset P3	8G P03	0.0, 1.0	Enable 8GT/s Preset P3.
Set Up	8GT/s Preset P4	8G P04	0.0, 1.0	Enable 8GT/s Preset P4.
Set Up	8GT/s Preset P5	8G P05	0.0, 1.0	Enable 8GT/s Preset P5.
Set Up	8GT/s Preset P6	8G P06	0.0, 1.0	Enable 8GT/s Preset P6.
Set Up	8GT/s Preset P7	8G P07	0.0, 1.0	Enable 8GT/s Preset P7.
Set Up	8GT/s Preset P8	8G P08	0.0, 1.0	Enable 8GT/s Preset P8.
Set Up	8GT/s Preset P9	8G P09	0.0, 1.0	Enable 8GT/s Preset P9.
Set Up	All CTLE Equalization	CTLE32GAAlldB	0.0, 1.0	Enable/disable All CTLE Equalization.
Set Up	All CTLE Equalization	CTLE64GJitter52UIAlldB	0.0, 1.0	Enable/disable All CTLE Equalization.
Set Up	All CTLE Equalization	CTLE64GPWJAlldB	0.0, 1.0	Enable/disable All CTLE Equalization.
Set Up	Auto Tune CTLE Equalization	CTLE64GJitter52UIAutoTune dB	0.0, 1.0	Enable/disable Auto Tune CTLE Equalization.
Set Up	Auto Tune CTLE Equalization	CTLE64GPWJAutoTunedB	0.0, 1.0	Enable/disable Auto Tune CTLE Equalization.
Set Up	Browse for the Jitter pattern file.	JitterBrowseConfigVar	1	This button is to browse for the Jitter pattern file. Browse for the Jitter pattern file.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Browse for the compliance pattern file.	ComplianceBrowseConfigVar	1	This button is to browse for the compliance pattern file. Browse for the compliance pattern file.
Set Up	CTLE 10dB Embedding	CTLE32G10dB	0.0, 1.0	Enable CTLE 10dB Embedding.
Set Up	CTLE 10dB Embedding	CTLE64GJitter52UI10dB	0.0, 1.0	Enable CTLE 10dB Embedding.
Set Up	CTLE 10dB Embedding	CTLE64GPWJ10dB	0.0, 1.0	Enable CTLE 10dB Embedding.
Set Up	CTLE 11dB Embedding	CTLE32G11dB	0.0, 1.0	Enable CTLE 11dB Embedding.
Set Up	CTLE 11dB Embedding	CTLE64GJitter52UI11dB	0.0, 1.0	Enable CTLE 11dB Embedding.
Set Up	CTLE 11dB Embedding	CTLE64GPWJ11dB	0.0, 1.0	Enable CTLE 11dB Embedding.
Set Up	CTLE 12dB Embedding	CTLE32G12dB	0.0, 1.0	Enable CTLE 12dB Embedding.
Set Up	CTLE 12dB Embedding	CTLE64GJitter52UI12dB	0.0, 1.0	Enable CTLE 12dB Embedding.
Set Up	CTLE 12dB Embedding	CTLE64GPWJ12dB	0.0, 1.0	Enable CTLE 12dB Embedding.
Set Up	CTLE 13dB Embedding	CTLE32G13dB	0.0, 1.0	Enable CTLE 13dB Embedding.
Set Up	CTLE 13dB Embedding	CTLE64GJitter52UI13dB	0.0, 1.0	Enable CTLE 13dB Embedding.
Set Up	CTLE 13dB Embedding	CTLE64GPWJ13dB	0.0, 1.0	Enable CTLE 13dB Embedding.
Set Up	CTLE 14dB Embedding	CTLE32G14dB	0.0, 1.0	Enable CTLE 14dB Embedding.
Set Up	CTLE 14dB Embedding	CTLE64GJitter52UI14dB	0.0, 1.0	Enable CTLE 14dB Embedding.
Set Up	CTLE 14dB Embedding	CTLE64GPWJ14dB	0.0, 1.0	Enable CTLE 14dB Embedding.
Set Up	CTLE 15dB Embedding	CTLE32G15dB	0.0, 1.0	Enable CTLE 15dB Embedding.
Set Up	CTLE 15dB Embedding	CTLE64GJitter52UI15dB	0.0, 1.0	Enable CTLE 15dB Embedding.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	CTLE 15dB Embedding	CTLE64GPWJ15dB	0.0, 1.0	Enable CTLE 15dB Embedding.
Set Up	CTLE 5dB Embedding	CTLE32G5dB	0.0, 1.0	Enable CTLE 5dB Embedding.
Set Up	CTLE 5dB Embedding	CTLE64GJitter52UI5dB	0.0, 1.0	Enable CTLE 5dB Embedding.
Set Up	CTLE 5dB Embedding	CTLE64GPWJ5dB	0.0, 1.0	Enable CTLE 5dB Embedding.
Set Up	CTLE 6dB Embedding	CTLE32G6dB	0.0, 1.0	Enable CTLE 6dB Embedding.
Set Up	CTLE 6dB Embedding	CTLE64GJitter52UI6dB	0.0, 1.0	Enable CTLE 6dB Embedding.
Set Up	CTLE 6dB Embedding	CTLE64GPWJ6dB	0.0, 1.0	Enable CTLE 6dB Embedding.
Set Up	CTLE 7dB Embedding	CTLE32G7dB	0.0, 1.0	Enable CTLE 7dB Embedding.
Set Up	CTLE 7dB Embedding	CTLE64GJitter52UI7dB	0.0, 1.0	Enable CTLE 7dB Embedding.
Set Up	CTLE 7dB Embedding	CTLE64GPWJ7dB	0.0, 1.0	Enable CTLE 7dB Embedding.
Set Up	CTLE 8dB Embedding	CTLE32G8dB	0.0, 1.0	Enable CTLE 8dB Embedding.
Set Up	CTLE 8dB Embedding	CTLE64GJitter52UI8dB	0.0, 1.0	Enable CTLE 8dB Embedding.
Set Up	CTLE 8dB Embedding	CTLE64GPWJ8dB	0.0, 1.0	Enable CTLE 8dB Embedding.
Set Up	CTLE 9dB Embedding	CTLE32G9dB	0.0, 1.0	Enable CTLE 9dB Embedding.
Set Up	CTLE 9dB Embedding	CTLE64GJitter52UI9dB	0.0, 1.0	Enable CTLE 9dB Embedding.
Set Up	CTLE 9dB Embedding	CTLE64GPWJ9dB	0.0, 1.0	Enable CTLE 9dB Embedding.
Set Up	Calibrate scope noise for PWJ (L0-L3) pattern	CalPwj	0.0, 1.0	Calibrate scope noise for PWJ (L0-L3) pattern.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Calibrate scope noise for all pattern	CalibrateAll	0.0, 1.0	Calibrate scope noise for all pattern.
Set Up	Calibrate scope noise for compliance pattern Q0	CalQ0	0.0, 1.0	Calibrate scope noise for compliance pattern Q0.
Set Up	Calibrate scope noise for jitter pattern	CalJitter	0.0, 1.0	Calibrate scope noise for jitter pattern.
Set Up	Calibration Handling Option	CalHandlingOpt	Run calibration, Ignore missing scope noise	Select the Scope Noise Calibration Handling Option. Select the Scope Noise Calibration Handling Option
Set Up	Calibration Option	ScopeNoiseOpt	Enable, Disable	Select the option of Compensate for Scope Noise. Select the option of Compensate for Scope Noise
Set Up	Clear for Jitter pattern file selection.	JitterClearConfigVar	1	This button is to clear the selected Jitter pattern file. Clear for Jitter pattern file selection.
Set Up	Clear for compliance pattern file selection.	ComplianceClearConfigVar	1	This button is to clear the selected compliance pattern file. Clear for compliance pattern file selection.
Set Up	Connect to 81150A/81160A (PFAG) now.	ConnectNowButton	1	Connect to 81150A/81160A (PFAG) is required before starts DUT Automation. Connect to 81150A/81160A (PFAG) now.
Set Up	Connection Differential Partner	OptConnectionDifferentialPartner	Every Other Channel, Adjacent Channels	Select Connection Differential Partner.
Set Up	Connection Type	OptConnectionType	Single-Ended, Differential	Select Connection Type.
Set Up	Deselect all 16GT/s presets.	DeselectAllPreset16GConfigVar	1	This button is to deselect all 16GT/s presets. Deselect all 16GT/s presets.
Set Up	Deselect all 32GT/s presets.	DeselectAllPreset32GConfigVar	1	This button is to deselect all 32GT/s presets. Deselect all 32GT/s presets.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Deselect all 64GT/s presets.	DeselectAllPreset64GConfigVar	1	This button is to deselect all 64GT/s presets. Deselect all 64GT/s presets.
Set Up	Deselect all 8GT/s presets.	DeselectAllPreset8GConfigVar	1	This button is to deselect all 8GT/s presets. Deselect all 8GT/s presets.
Set Up	Device Directory	OfflineDeviceDirectoryName	New Device1	Available directories to run Analyze Captured Waveforms operation.
Set Up	Device Name	DeviceName	(Accepts user-defined text)	Name for the DUT in testing.
Set Up	DevicePCIERev	DevicePCIERev	PCIE 4.0, PCIE 5.0, PCIE 6.0	Select the PCI Express device specification to use.
Set Up	Enable Collective Data Acquisition	PresetWfmCollectiveAcqConfigVar	0.0, 1.0	Enable Collective Data Acquisition.
Set Up	Enable DUT Automation	DutAutomation	0.0, 1.0	Enable DUT Automation.
Set Up	Enable Workshop Compliance Mode	Workshop Compliance Mode	0.0, 1.0	Enable Workshop Compliance Mode.
Set Up	IP Address of 81150A/81160A (PFAG)	PFAGIPAddress	(Accepts user-defined text)	Specifies the IP address of 81150A/81160A (PFAG). Specifies the IP address of 81150A/81160A (PFAG)
Set Up	Manual Input Compliance Pattern File Directory	ManualInputCompliancePatternFileDirectory	(Accepts user-defined text)	Directory of manual input Compliance pattern file.
Set Up	Manual Input Jitter Pattern File Directory	ManualInputJitterPatternFileDirectory	(Accepts user-defined text)	Directory of manual input Jitter pattern file.
Set Up	OfflineDataLane	cbOfflineDataLane	00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 10, 11, 12, 13, 14, 15	
Set Up	OfflineDataRate	OfflineDataRate	2.5 GT/s, 5.0 GT/s, 8.0 GT/s, 16.0 GT/s, 32.0 GT/s, 64.0 GT/s	

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	OfflineDeemphasis	OfflineDeemphasis	-3.5dB, -6.0dB	
Set Up	OfflinePowerLevel	cbOfflinePowerLevel	Full, Half	
Set Up	OfflinePreset	OfflinePreset	Q00, Q01, Q02, Q03, Q04, Q05, Q06, Q07, Q08, Q09, Q10, PWJClock, JitterData, HighLowSwingData	
Set Up	OfflineRefClk	cbOfflineRefClk	Clean Clock, SSC	
Set Up	OfflineSRIS	cbOfflineSRIS	None, Enabled	
Set Up	OfflineSignalType	OfflineSignalType	Data, UI03, UI12	
Set Up	OfflineTestPoint	cbOfflineTestPoint	Base - Transmitter Tests, CEM - End Point Tests, CEM - Root Complex Tests, Reference Clock Tests	
Set Up	OfflineTestPointChannel	cbOfflineTestPointChannel	Min, Max	
Set Up	PFAG Connection Option	PFAGConnectionOpt	IP Address, SICL Address	Select the PFAG Connection Option. Select the PFAG Connection Option
Set Up	Perform Done operation to apply all setting changes.	DoneConnectionSetupConfigVar	1	This button is required to click/set in order to apply on all the settings have been set in this Connection Setup window. Perform Done operation to apply all setting changes.
Set Up	Perform Done operation to apply all setting changes.	DoneDeviceDefConfigVar	1	This button is required to click/set in order to apply on all the settings have been set in this Device Definition window. Perform Done operation to apply all setting changes.
Set Up	Perform Done operation to apply all setting changes.	DoneScopeNoiseCalibrationSetupConfigVar	1	This button is required to click/set in order to apply on all the settings have been set in this Scope Noise Calibration Setup window. Perform Done operation to apply all setting changes.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Perform scope noise calibration.	StartScopeNoiseCalibration ConfigVar	1	This button is required to start to calibrate scope noise operation. Perform scope noise calibration.
Set Up	SICL Address of 81150A/81160A (PFAG)	PFAGSiclAddress	(Accepts user-defined text)	Specifies the SICL address of 81150A/81160A (PFAG). Specifies the SICL address of 81150A/81160A (PFAG)
Set Up	Saved Files Directory	SavedFilesDirectory	(Accepts user-defined text)	Directory to save output files from Workshop Mode Test.
Set Up	Select 16.0 GT/s related tests	16.0 GT/s	0.0, 1.0	Select 16.0 GT/s related tests.
Set Up	Select 2.5 GT/s related tests	2.5 GT/s	0.0, 1.0	Select 2.5 GT/s related tests.
Set Up	Select 32.0 GT/s related tests	32.0 GT/s	0.0, 1.0	Select 32.0 GT/s related tests.
Set Up	Select 5.0 GT/s related tests	5.0 GT/s	0.0, 1.0	Select 5.0 GT/s related tests.
Set Up	Select 64.0 GT/s related tests	64.0 GT/s	0.0, 1.0	Select 64.0 GT/s related tests.
Set Up	Select 8.0 GT/s related tests	8.0 GT/s	0.0, 1.0	Select 8.0 GT/s related tests.
Set Up	Select De-Emphasis -3.5dB for data speed 5GT/s	DeEmphasis3P5dBConfigVar	0.0, 1.0	Select De-Emphasis -3.5dB for data speed 5GT/s Select De-Emphasis -3.5dB for data speed 5GT/s
Set Up	Select De-Emphasis -6.0dB for data speed 5GT/s	DeEmphasis6P0dBConfigVar	0.0, 1.0	Select De-Emphasis -6.0dB for data speed 5GT/s Select De-Emphasis -6.0dB for data speed 5GT/s
Set Up	Select Lane 0	Lane0	0.0, 1.0	Select Lane 0 Select Lane 0
Set Up	Select Lane 1	Lane1	0.0, 1.0	Select Lane 1 Select Lane 1
Set Up	Select Lane 10	Lane10	0.0, 1.0	Select Lane 10 Select Lane 10
Set Up	Select Lane 11	Lane11	0.0, 1.0	Select Lane 11 Select Lane 11
Set Up	Select Lane 12	Lane12	0.0, 1.0	Select Lane 12 Select Lane 12
Set Up	Select Lane 13	Lane13	0.0, 1.0	Select Lane 13 Select Lane 13

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Select Lane 14	Lane14	0.0, 1.0	Select Lane 14 Select Lane 14
Set Up	Select Lane 15	Lane15	0.0, 1.0	Select Lane 15 Select Lane 15
Set Up	Select Lane 2	Lane2	0.0, 1.0	Select Lane 2 Select Lane 2
Set Up	Select Lane 3	Lane3	0.0, 1.0	Select Lane 3 Select Lane 3
Set Up	Select Lane 4	Lane4	0.0, 1.0	Select Lane 4 Select Lane 4
Set Up	Select Lane 5	Lane5	0.0, 1.0	Select Lane 5 Select Lane 5
Set Up	Select Lane 6	Lane6	0.0, 1.0	Select Lane 6 Select Lane 6
Set Up	Select Lane 7	Lane7	0.0, 1.0	Select Lane 7 Select Lane 7
Set Up	Select Lane 8	Lane8	0.0, 1.0	Select Lane 8 Select Lane 8
Set Up	Select Lane 9	Lane9	0.0, 1.0	Select Lane 9 Select Lane 9
Set Up	Select Switch Matrix.	optSwitchMatrix	No Switch Matrix, BitifEye BIT 2100, Keysight U3020A S26	Select SwitchMatrix.
Set Up	Select all 16GT/s presets.	SelectAllPreset16GConfigVar	1	This button is to select all 16GT/s presets. Select all 16GT/s presets.
Set Up	Select all 32GT/s presets.	SelectAllPreset32GConfigVar	1	This button is to select all 32GT/s presets. Select all 32GT/s presets.
Set Up	Select all 64GT/s presets.	SelectAllPreset64GConfigVar	1	This button is to select all 64GT/s presets. Select all 64GT/s presets.
Set Up	Select all 8GT/s presets.	SelectAllPreset8GConfigVar	1	This button is to select all 8GT/s presets. Select all 8GT/s presets.
Set Up	Select clock channel	DiffClockChannelConfigVar	Channel-1, Channel-2, Channel-3, Channel-4	Select clock channel
Set Up	Select clock channel +	SingleEndedClockChannelPConfigVar	Channel-1, Channel-2	Select clock channel +.
Set Up	Select clock channel -	SingleEndedClockChannelNConfigVar	Channel-3, Channel-4	Select clock channel -.
Set Up	Select data channel	DiffDataChannelConfigVar	Channel-1, Channel-2, Channel-3, Channel-4	Select data channel
Set Up	Select data channel +	SingleEndedDataChannelPCConfigVar	Channel-1, Channel-2	Select data channel +.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Select data channel -	SingleEndedDataChannelINConfigVar	Channel-3, Channel-4	Select data channel -.
Set Up	Select if DUT is enable lane reversal	ChkReverseLaneDUT	0.0, 1.0	Select if DUT is enable lane reversal.
Set Up	Select switching modules in BIT2100 Frame.	BIT2100Modules	2xSP4T, 2xSP6T, 2xSP8T	Select switching modules in BIT2100 Frame.
Set Up	Select the Power Level.	PowerLevelConfigVar	Full, Half	Select the Power Level.
Set Up	Select the Reference Clock Type.	RefClkConfigVar	Clean Clock, SSC	Select the Reference Clock Type.
Set Up	Select the SRIS type.	SRISEnabledConfigVar	None, Enabled	Select the SRIS type.
Set Up	Setup toggle source now.	ToggleSetupButton	1	Setup the toggle source for DUT Automation now. Setup toggle source now.
Set Up	Test Point	TestPoint	Base - Transmitter Tests, CEM - End Point Tests, CEM - Root Complex Tests, Reference Clock Tests	Select the PCIExpress device test point to be tested.
Set Up	Test Point Preset Test	TestPointPresetTest	0.0, 1.0	Select to run Equalization Preset Tests.
Set Up	Toggle Source	ToggleSourceOpt	81150A / 81160A, CAL OUT (100MHz)	Select the toggle source to toggle your DUT. Select the toggle source to toggle your DUT
Set Up	Transfer Function Path for 32GT/s Lane 0	TFPath32GLane0	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 0 Transfer Function Path for 32GT/s Lane 0

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Transfer Function Path for 32GT/s Lane 1	TFPath32GLane1	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 1 Transfer Function Path for 32GT/s Lane 1
Set Up	Transfer Function Path for 32GT/s Lane 10	TFPath32GLane10	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 10 Transfer Function Path for 32GT/s Lane 10
Set Up	Transfer Function Path for 32GT/s Lane 11	TFPath32GLane11	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 11 Transfer Function Path for 32GT/s Lane 11
Set Up	Transfer Function Path for 32GT/s Lane 12	TFPath32GLane12	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 12 Transfer Function Path for 32GT/s Lane 12
Set Up	Transfer Function Path for 32GT/s Lane 13	TFPath32GLane13	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 13 Transfer Function Path for 32GT/s Lane 13
Set Up	Transfer Function Path for 32GT/s Lane 14	TFPath32GLane14	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 14 Transfer Function Path for 32GT/s Lane 14
Set Up	Transfer Function Path for 32GT/s Lane 15	TFPath32GLane15	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 15 Transfer Function Path for 32GT/s Lane 15

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Transfer Function Path for 32GT/s Lane 2	TFPath32GLane2	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 2 Transfer Function Path for 32GT/s Lane 2
Set Up	Transfer Function Path for 32GT/s Lane 3	TFPath32GLane3	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 3 Transfer Function Path for 32GT/s Lane 3
Set Up	Transfer Function Path for 32GT/s Lane 4	TFPath32GLane4	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 4 Transfer Function Path for 32GT/s Lane 4
Set Up	Transfer Function Path for 32GT/s Lane 5	TFPath32GLane5	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 5 Transfer Function Path for 32GT/s Lane 5
Set Up	Transfer Function Path for 32GT/s Lane 6	TFPath32GLane6	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 6 Transfer Function Path for 32GT/s Lane 6
Set Up	Transfer Function Path for 32GT/s Lane 7	TFPath32GLane7	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 7 Transfer Function Path for 32GT/s Lane 7
Set Up	Transfer Function Path for 32GT/s Lane 8	TFPath32GLane8	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 8 Transfer Function Path for 32GT/s Lane 8

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Transfer Function Path for 32GT/s Lane 9	TFPath32GLane9	-, NRC_TL_5dB.tf4, NRC_TL_5p5dB.tf4, NRC_TL_6dB.tf4, NRC_TL_6p5dB.tf4, NRC_TL_7dB.tf4, NRC_TL_7p5dB.tf4	Transfer Function Path for 32GT/s Lane 9 Transfer Function Path for 32GT/s Lane 9
Set Up	Try toggle DUT now.	ToggleNowButton	1	Try toggle DUT to next state. Try toggle DUT now.
Set Up	Use Local Saved Waveform	UseLocalSavedWaveform	0.0, 1.0	Use Local Saved Waveform.
Set Up	User Comment	UserComments	(Accepts user-defined text)	Additional comments for the DUT in testing. Additional comments for the DUT in testing.
* Limited availability: Availability of this setting depends upon the oscilloscope model and installed license options.				

3 Test Names and IDs

The following table shows the mapping between each test's numeric ID and name. The numeric ID is required by various remote interface methods.

- Name – The name of the test as it appears on the user interface **Select Tests** tab.
- Test ID – The number to use with the RunTests method.
- Description – The description of the test as it appears on the user interface **Select Tests** tab.

For example, if the graphical user interface displays this tree in the **Select Tests** tab:

- All Tests
 - Rise Time
 - Fall Time

then you would expect to see something like this in the table below:

Table 3 Example Test Names and IDs

Name	Test ID	Description
Fall Time	110	Measures clock fall time.
Rise Time	100	Measures clock rise time.

and you would run these tests remotely using:

ARSL syntax

```
arsl -a ipaddress -c "SelectedTests '100,110'"  
arsl -a ipaddress -c "Run"
```

C# syntax

```
remoteAte.SelectedTests = new int[] {100,110};  
remoteAte.Run();
```

Here are the actual Test names and IDs used by this application. Listed at the end, you may also find:

- Deprecated IDs and their replacements.
- Macro IDs which may be used to select multiple related tests at the same time.

NOTE

The file, "TestInfo.txt", which may be found in the same directory as this help file, contains all of the information found in the table below in a format suitable for parsing.

Table 4 Test IDs and Names

Name	TestID	Description
Base Tx Test - Workshop Mode Test (16.0 GT/s)	4049000	
Base Tx Test - Workshop Mode Test (16.0 GT/s)	5049000	
Base Tx Test - Workshop Mode Test (16.0 GT/s)	6049000	
Base Tx Test - Workshop Mode Test (2.5 GT/s)	4019000	
Base Tx Test - Workshop Mode Test (2.5 GT/s)	5019000	
Base Tx Test - Workshop Mode Test (2.5 GT/s)	6019000	
Base Tx Test - Workshop Mode Test (32.0 GT/s)	5059000	
Base Tx Test - Workshop Mode Test (32.0 GT/s)	6059000	
Base Tx Test - Workshop Mode Test (5.0 GT/s)	4029000	
Base Tx Test - Workshop Mode Test (5.0 GT/s)	5029000	
Base Tx Test - Workshop Mode Test (5.0 GT/s)	6029000	
Base Tx Test - Workshop Mode Test (64.0 GT/s)	6069000	
Base Tx Test - Workshop Mode Test (8.0 GT/s)	4039000	
Base Tx Test - Workshop Mode Test (8.0 GT/s)	5039000	

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Base Tx Test - Workshop Mode Test (8.0 GT/s)	6039000	
EndPoint Tests - Workshop Mode Test (2.5 GT/s)	5019200	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in table 4-8 of section 4.8.13 of the PCI Express Card Electromechanical (CEM) Specification, Rev 5.0, as measured after the connector with an ideal load.
EndPoint Tests - Workshop Mode Test (8.0 GT/s)	5039200	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in table 4-13 of section 4.8.3 of the PCI Express Card Electromechanical (CEM) Specification, Rev 5.0, as measured after the connector with an ideal load.
EndPoint Tests - Workshop Mode Test - 3.5dB (5.0 GT/s)	5029200	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in table 4-10 of section 4.8.2 of the PCI Express Card Electromechanical Specification (CEM) Rev 5.0, as measured at the card edge-fingers. This test does NOT validate the receiver's tolerance, but rather that the signal at the receiver meets the specifications in figure 4-7.
EndPoint Tests - Workshop Mode Test - 6.0dB (5.0 GT/s)	5029201	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in table 4-12 of section 4.8.2 of the PCI Express Card Electromechanical Specification (CEM) Rev 5.0, as measured at the card edge-fingers. This test does NOT validate the receiver's tolerance, but rather that the signal at the receiver meets the specifications in figure 4-7.
EndPoint Tests - Workshop Mode Test - Max Channel (16.0 GT/s)	5049201	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified section 4.8.4 of the PCI Express Card Electromechanical Specification (CEM) Rev 4.0, as measured at the card edge-fingers.
EndPoint Tests - Workshop Mode Test - Max Channel - Signal Quality Test (32.0 GT/s)	5059201	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests - Workshop Mode Test - Min Channel (16.0 GT/s)	5049200	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified section 4.8.4 of the PCI Express Card Electromechanical Specification (CEM) Rev 4.0, as measured at the card edge-fingers.
EndPoint Tests - Workshop Mode Test - Min Channel - Base Jitter Test (32.0 GT/s)	5059200	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
EndPoint Tests, Eye-Width (16.0 GT/s)	5042009	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Eye-Width (2.5 GT/s)	5012009	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [peak-to-peak jitter].
EndPoint Tests, Eye-Width (32.0 GT/s)	5052009	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Eye-Width (8.0 GT/s)	5032009	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [TJ at BER -12].
EndPoint Tests, Eye-Width -3.5dB with crosstalk (5.0 GT/s)	5022009	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [TJ at BER-12].
EndPoint Tests, Eye-Width -3.5dB without crosstalk (5.0 GT/s)	5022010	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [TJ at BER-12].
EndPoint Tests, Eye-Width -6.0dB with crosstalk (5.0 GT/s)	5022011	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [peak-to-peak jitter].
EndPoint Tests, Eye-Width -6.0dB without crosstalk (5.0 GT/s)	5022012	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [peak-to-peak jitter].
EndPoint Tests, Maximum Deterministic Jitter -3.5dB with crosstalk (5.0 GT/s)	5022017	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Maximum Deterministic Jitter -3.5dB without crosstalk (5.0 GT/s)	5022018	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Maximum Deterministic Jitter -6.0dB with crosstalk (5.0 GT/s)	5022019	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Maximum Deterministic Jitter -6.0dB without crosstalk (5.0 GT/s)	5022020	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Median to Max Jitter (2.5 GT/s)	5012004	This test measures the maximum time between the jitter median and maximum deviation from the median.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
EndPoint Tests, Peak Differential Output Voltage (Non-Transition)(16.0 GT/s)	5042006	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Peak Differential Output Voltage (Non-Transition)(2.5 GT/s)	5012006	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
EndPoint Tests, Peak Differential Output Voltage (Non-Transition)(32.0 GT/s)	5052006	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
EndPoint Tests, Peak Differential Output Voltage (Non-Transition)(8.0 GT/s)	5032006	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
EndPoint Tests, Peak Differential Output Voltage (Transition)(16.0 GT/s)	5042005	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Peak Differential Output Voltage (Transition)(2.5 GT/s)	5012005	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
EndPoint Tests, Peak Differential Output Voltage (Transition)(32.0 GT/s)	5052005	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
EndPoint Tests, Peak Differential Output Voltage (Transition)(8.0 GT/s)	5032005	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
EndPoint Tests, Peak Differential Output Voltage -3.5dB (Non-Transition)(5.0 GT/s)	5022006	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
EndPoint Tests, Peak Differential Output Voltage -3.5dB (Transition)(5.0 GT/s)	5022005	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
EndPoint Tests, Peak Differential Output Voltage -6.0dB (Non-Transition)(5.0 GT/s)	5022008	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
EndPoint Tests, Peak Differential Output Voltage -6.0dB (Transition)(5.0 GT/s)	5022007	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
EndPoint Tests, RMS Random Jitter -3.5dB with crosstalk (5.0 GT/s)	5022013	This test verifies RMS Random Jitter, it is informative only.
EndPoint Tests, RMS Random Jitter -3.5dB without crosstalk (5.0 GT/s)	5022014	This test verifies RMS Random Jitter, it is informative only.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
EndPoint Tests, RMS Random Jitter -6.0dB with crosstalk (5.0 GT/s)	5022015	This test verifies RMS Random Jitter, it is informative only.
EndPoint Tests, RMS Random Jitter -6.0dB without crosstalk (5.0 GT/s)	5022016	This test verifies RMS Random Jitter, it is informative only.
EndPoint Tests, Template Tests (16.0 GT/s)	5042002	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Template Tests (2.5 GT/s)	5012002	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers. This test does NOT validate the receiver's tolerance, but rather that the signal at the receiver meets the specifications.
EndPoint Tests, Template Tests (32.0 GT/s)	5052002	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Template Tests (8.0 GT/s)	5032002	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Template Tests -3.5dB (5.0 GT/s)	5022002	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers. This test does NOT validate the receiver's tolerance, but rather that the signal at the receiver meets the specifications.
EndPoint Tests, Template Tests -6.0dB (5.0 GT/s)	5022003	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers. This test does NOT validate the receiver's tolerance, but rather that the signal at the receiver meets the specifications.
EndPoint Tests, Total Jitter at BER-12 -3.5dB with crosstalk (5.0 GT/s)	5022021	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Total Jitter at BER-12 -3.5dB without crosstalk (5.0 GT/s)	5022022	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
EndPoint Tests, Total Jitter at BER-12 -6.0dB with crosstalk (5.0 GT/s)	5022023	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Total Jitter at BER-12 -6.0dB without crosstalk (5.0 GT/s)	5022024	Add-in cards must meet the Add-in Card Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
EndPoint Tests, Uncorrelated Deterministic Jitter (32.0 GT/s)	5052013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
EndPoint Tests, Uncorrelated Deterministic Pulse Width Jitter (16.0 GT/s)	5042011	This test verifies maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD, it is informative only.
EndPoint Tests, Uncorrelated Deterministic Pulse Width Jitter (32.0 GT/s)	5052011	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range. This test required PWJ clock pattern.
EndPoint Tests, Uncorrelated Total Jitter (32.0 GT/s)	5052012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
EndPoint Tests, Uncorrelated Total Pulse Width Jitter (16.0 GT/s)	5042010	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range. This test required PWJ clock pattern.
EndPoint Tests, Uncorrelated Total Pulse Width Jitter (32.0 GT/s)	5052010	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range. This test required PWJ clock pattern.
EndPoint Tests, Unit Interval (16.0 GT/s)	5042000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
EndPoint Tests, Unit Interval (32.0 GT/s)	5052000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
EndPoint Tests, Unit interval (2.5 GT/s)	5012000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
EndPoint Tests, Unit interval (8.0 GT/s)	5032000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
EndPoint Tests, Unit interval -3.5dB (5.0 GT/s)	5022000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
EndPoint Tests, Unit interval -6.0dB (5.0 GT/s)	5022001	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
Reference Clock, Absolute Crossing Point Voltage	4014008	This test verifies that the absolute crossing point voltage of the reference clock single-ended waveforms is within the allowed range.
Reference Clock, Absolute Crossing Point Voltage	5014008	This test verifies that the absolute crossing point voltage of the reference clock single-ended waveforms is within the allowed range.
Reference Clock, Absolute Crossing Point Voltage	6014008	This test verifies that the absolute crossing point voltage of the reference clock single-ended waveforms is within the allowed range.
Reference Clock, Absolute Max Input Voltage	4014014	This test verifies that the absolute maximum input voltage of the reference clock is within the allowed range.
Reference Clock, Absolute Max Input Voltage	5014014	This test verifies that the absolute maximum input voltage of the reference clock is within the allowed range.
Reference Clock, Absolute Max Input Voltage	6014014	This test verifies that the absolute maximum input voltage of the reference clock is within the allowed range.
Reference Clock, Absolute Min Input Voltage	4014016	This test verifies that the absolute minimum input voltage of the reference clock is within the allowed range.
Reference Clock, Absolute Min Input Voltage	5014016	This test verifies that the absolute minimum input voltage of the reference clock is within the allowed range.
Reference Clock, Absolute Min Input Voltage	6014016	This test verifies that the absolute minimum input voltage of the reference clock is within the allowed range.
Reference Clock, Average Clock Period	4014004	This test verifies that the average clock period accuracy of the differential waveform is within the allowed range.
Reference Clock, Average Clock Period	5014004	This test verifies that the average clock period accuracy of the differential waveform is within the allowed range.
Reference Clock, Average Clock Period	6014004	This test verifies that the average clock period accuracy of the differential waveform is within the allowed range.
Reference Clock, Average Clock Period (32.0GT/s)	5054004	This test verifies that the average clock period accuracy of the differential waveform is within the allowed range. This test is applicable for devices that support 32.0GT/s data speed.
Reference Clock, Average Clock Period (32.0GT/s)	6054004	This test verifies that the average clock period accuracy of the differential waveform is within the allowed range. This test is applicable for devices that support 32.0GT/s data speed.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Reference Clock, Average Clock Period (32.0GT/s, SRIS)	5054005	This test verifies that the average clock period accuracy of the differential waveform is within the allowed range. This test is applicable for devices that support 32.0GT/s speed with SRIS mode.
Reference Clock, Average Clock Period (32.0GT/s, SRIS)	6054005	This test verifies that the average clock period accuracy of the differential waveform is within the allowed range. This test is applicable for devices that support 32.0GT/s speed with SRIS mode.
Reference Clock, Average Clock Period (64.0GT/s)	6064004	This test verifies that the average clock period accuracy of the differential waveform is within the allowed range. This test is applicable for devices that support 64.0GT/s data speed.
Reference Clock, Average Clock Period (64.0GT/s, SRIS)	6064005	This test verifies that the average clock period accuracy of the differential waveform is within the allowed range. This test is applicable for devices that support 64.0GT/s speed with SRIS mode.
Reference Clock, Clock Frequency (Common Clk)	5014024	This test verifies that the measured reference clock frequency, FREFCLK, is within than the allowed frequency range.
Reference Clock, Clock Frequency (Common Clk)	6014024	This test verifies that the measured reference clock frequency, FREFCLK, is within than the allowed frequency range.
Reference Clock, Clock Frequency (Common Clk) (16.0 GT/s)	4044024	This test verifies that the measured reference clock frequency, FREFCLK, is within than the allowed frequency range.
Reference Clock, Clock Frequency (Common Clk) (8.0 GT/s)	4034024	This test verifies that the measured reference clock frequency, FREFCLK, is within than the allowed frequency range.
Reference Clock, Clock Frequency (Common Clk)(32.0 GT/s)	5054024	This test verifies that the measured reference clock frequency, FREFCLK, is within than the allowed frequency range.
Reference Clock, Clock Frequency (Common Clk)(32.0 GT/s)	6054024	This test verifies that the measured reference clock frequency, FREFCLK, is within than the allowed frequency range.
Reference Clock, Clock Frequency (Common Clk)(64.0 GT/s)	6064024	This test verifies that the measured reference clock frequency, FREFCLK, is within than the allowed frequency range.
Reference Clock, Differential Input High Voltage	4014006	This test verifies that the high voltage of the reference clock differential waveform is greater than the minimum allowed value.
Reference Clock, Differential Input High Voltage	5014006	This test verifies that the high voltage of the reference clock differential waveform is greater than the minimum allowed value.
Reference Clock, Differential Input High Voltage	6014006	This test verifies that the high voltage of the reference clock differential waveform is greater than the minimum allowed value.
Reference Clock, Differential Input Low Voltage	4014007	This test verifies that the low voltage of the reference clock differential waveform is greater than the maximum allowed value.
Reference Clock, Differential Input Low Voltage	5014007	This test verifies that the low voltage of the reference clock differential waveform is greater than the maximum allowed value.
Reference Clock, Differential Input Low Voltage	6014007	This test verifies that the low voltage of the reference clock differential waveform is greater than the maximum allowed value.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Reference Clock, Duty Cycle	4014005	This test verifies that the duty cycle of the reference clock differential waveform is within the allowed range.
Reference Clock, Duty Cycle	5014005	This test verifies that the duty cycle of the reference clock differential waveform is within the allowed range.
Reference Clock, Duty Cycle	6014009	This test verifies that the duty cycle of the reference clock differential waveform is within the allowed range.
Reference Clock, Falling Edge Rate	4014003	This test verifies that the falling edge rate of the waveform is within the allowed range. The value is measured from -150mV to +150mV on the differential waveform and the measurement window is centered on the differential zero crossing.
Reference Clock, Falling Edge Rate	5014003	This test verifies that the rising edge rate of the waveform is within the allowed range. The value is measured from -150mV to +150mV on the differential waveform and the measurement window is centered on the differential zero crossing.
Reference Clock, Falling Edge Rate	6014003	This test verifies that the rising edge rate of the waveform is within the allowed range. The value is measured from -150mV to +150mV on the differential waveform and the measurement window is centered on the differential zero crossing.
Reference Clock, Max SSC df/dt (Common Clk)	5014021	This test verifies that the reference clock maximum SSC df/dt is within the allowed range.
Reference Clock, Max SSC df/dt (Common Clk)	6014021	This test verifies that the reference clock maximum SSC df/dt is within the allowed range.
Reference Clock, PCI-SIG Reference Clock Jitter (16.0 GT/s)	5044013	This test will run PCI-SIG Reference Clock Jitter for PCIe 5.0 Generation.
Reference Clock, PCI-SIG Reference Clock Jitter (2.5 GT/s)	5014013	This test will run PCI-SIG Reference Clock Jitter for PCIe 5.0 Generation.
Reference Clock, PCI-SIG Reference Clock Jitter (32.0 GT/s)	5054013	This test will run PCI-SIG Reference Clock Jitter for PCIe 5.0 Generation.
Reference Clock, PCI-SIG Reference Clock Jitter (5.0 GT/s)	5024013	This test will run PCI-SIG Reference Clock Jitter for PCIe 5.0 Generation.
Reference Clock, PCI-SIG Reference Clock Jitter (8.0 GT/s)	5034013	This test will run PCI-SIG Reference Clock Jitter for PCIe 5.0 Generation.
Reference Clock, Peak to Peak Jitter (Common Clk) (2.5 GT/s)	5014011	This test verifies that the measured Peak to Peak jitter, TREFCLK-PP, is less than the maximum allowed value.
Reference Clock, Peak to Peak Jitter (Common Clk) (2.5 GT/s)	6014011	This test verifies that the measured Peak to Peak jitter, TREFCLK-PP, is less than the maximum allowed value.
Reference Clock, Peak to Peak Jitter (Common Clk) (PCIe4 2.5 GT/s)	4014011	This test verifies that the measured Peak to Peak jitter, TREFCLK-PP, is less than the maximum allowed value.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Reference Clock, RMS Jitter (Common Clk) (16.0 GT/s)	4044011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (16.0 GT/s)	5044011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (16.0 GT/s)	6044011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (32.0 GT/s)	5054011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (32.0 GT/s)	6054011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (5.0 GT/s)	4024011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (5.0 GT/s)	5024011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (5.0 GT/s)	6024011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (64.0 GT/s)	6064011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (8.0 GT/s)	4034011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (8.0 GT/s)	5034011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, RMS Jitter (Common Clk) (8.0 GT/s)	6034011	This test verifies that the measured RMS jitter, TREFCLK-RMS, is less than the maximum allowed value.
Reference Clock, Rise-Fall Matching	4014018	This test verifies that the rising edge rate (REFCLK+) to falling edge rate (REFCLK-) matching is within the allowed range.
Reference Clock, Rise-Fall Matching	5014018	This test verifies that the rising edge rate (REFCLK+) to falling edge rate (REFCLK-) matching is within the allowed range.
Reference Clock, Rise-Fall Matching	6014018	This test verifies that the rising edge rate (REFCLK+) to falling edge rate (REFCLK-) matching is within the allowed range.
Reference Clock, Rising Edge Rate	4014002	This test verifies that the rising edge rate of the waveform is within the allowed range. The value is measured from -150mV to +150mV on the differential waveform and the measurement window is centered on the differential zero crossing.
Reference Clock, Rising Edge Rate	5014002	This test verifies that the rising edge rate of the waveform is within the allowed range. The value is measured from -150mV to +150mV on the differential waveform and the measurement window is centered on the differential zero crossing.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Reference Clock, Rising Edge Rate	6014002	This test verifies that the rising edge rate of the waveform is within the allowed range. The value is measured from -150mV to +150mV on the differential waveform and the measurement window is centered on the differential zero crossing.
Reference Clock, SSC deviation (Common Clk)	5014020	This test verifies that the reference clock SSC deviation is within the allowed range.
Reference Clock, SSC deviation (Common Clk)	6014020	This test verifies that the reference clock SSC deviation is within the allowed range.
Reference Clock, SSC deviation (Common Clk) (16.0 GT/s)	4044020	This test verifies that the reference clock SSC deviation is within the allowed range.
Reference Clock, SSC deviation (Common Clk) (5.0 GT/s)	4024020	This test verifies that the reference clock SSC deviation is within the allowed range.
Reference Clock, SSC deviation (Common Clk) (8.0 GT/s)	4034020	This test verifies that the reference clock SSC deviation is within the allowed range.
Reference Clock, SSC frequency range (Common Clk)	5014019	This test verifies that the reference clock SSC frequency is within the allowed range.
Reference Clock, SSC frequency range (Common Clk)	6014019	This test verifies that the reference clock SSC frequency is within the allowed range.
Reference Clock, SSC frequency range (Common Clk) (16.0 GT/s)	4044019	This test verifies that the reference clock SSC frequency is within the allowed range.
Reference Clock, SSC frequency range (Common Clk) (5.0 GT/s)	4024019	This test verifies that the reference clock SSC frequency is within the allowed range.
Reference Clock, SSC frequency range (Common Clk) (8.0 GT/s)	4034019	This test verifies that the reference clock SSC frequency is within the allowed range.
Reference Clock, Variation of VCross	4014010	This test verifies that the variation of VCross over all rising clock edges is within the allowed range.
Reference Clock, Variation of VCross	5014010	This test verifies that the variation of VCross over all rising clock edges is within the allowed range.
Reference Clock, Variation of VCross	6014010	This test verifies that the variation of VCross over all rising clock edges is within the allowed range.
RootComplex Tests - Workshop Mode Test (2.5 GT/s)	5019100	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in table 4-8 of section 4.8.13 of the PCI Express Card Electromechanical (CEM) Specification, Rev 5.0, as measured after the connector with an ideal load.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
RootComplex Tests - Workshop Mode Test (5.0 GT/s)	5029100	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in table 4-25 of section 4.8.14 of the PCI Express Card Electromechanical (CEM) Specification, Rev 5.0, as measured after the connector with an ideal load.
RootComplex Tests - Workshop Mode Test (8.0 GT/s)	5039100	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in table 4-27 of section 4.8.15 of the PCI Express Card Electromechanical (CEM) Specification, Rev 5.0, as measured after the connector with an ideal load.
RootComplex Tests - Workshop Mode Test - Max Channel (16.0 GT/s)	5049101	System Board must meet the System Board Transmitter Path Compliance Eye Requirements specified section 4.8.15 of the PCI Express Card Electromechanical Specification (CEM) Rev 5.0. This test is run without InfiniiSim embedding and without an ISI channel added to the CBB.
RootComplex Tests - Workshop Mode Test - Max Channel - Signal Quality Test (32.0 GT/s)	5059101	System Board must meet the System Board Transmitter Path Compliance Eye Requirements specified section 4.8.15 of the PCI Express Card Electromechanical Specification (CEM) Rev 5.0. This test is run without InfiniiSim embedding and without an ISI channel added to the CBB.
RootComplex Tests - Workshop Mode Test - Min Channel (16.0 GT/s)	5049100	System Board must meet the System Board Transmitter Path Compliance Eye Requirements specified section 4.8.15 of the PCI Express Card Electromechanical Specification (CEM) Rev 5.0. This test is run without InfiniiSim embedding and without an ISI channel added to the CBB.
RootComplex Tests - Workshop Mode Test - Min Channel - Base Jitter Test (32.0 GT/s)	5059100	System Board must meet the System Board Transmitter Path Compliance Eye Requirements specified section 4.8.15 of the PCI Express Card Electromechanical Specification (CEM) Rev 5.0. This test is run without InfiniiSim embedding and without an ISI channel added to the CBB.
RootComplex Tests, Eye-Width (16.0 GT/s)	5043009	System Board must meet the System Board Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM).
RootComplex Tests, Eye-Width (2.5 GT/s)	5013009	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [peak-to-peak jitter].
RootComplex Tests, Eye-Width (32.0 GT/s)	5053009	System Board must meet the System Board Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM).
RootComplex Tests, Eye-Width (8.0 GT/s)	5033009	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [TJ at BER -12].

Table 4 Test IDs and Names (continued)

Name	TestID	Description
RootComplex Tests, Eye-Width with crosstalk (5.0 GT/s)	5023009	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [peak-to-peak jitter].
RootComplex Tests, Eye-Width without crosstalk (5.0 GT/s)	5023010	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [peak-to-peak jitter].
RootComplex Tests, Maximum Deterministic Jitter with crosstalk (5.0 GT/s)	5023017	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range.
RootComplex Tests, Maximum Deterministic Jitter without crosstalk (5.0 GT/s)	5023018	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range.
RootComplex Tests, Median to Max Jitter (2.5 GT/s)	5013004	This test measures the maximum time between the jitter median and maximum deviation from the median.
RootComplex Tests, Peak Differential Output Voltage (Non-Transition)(16.0 GT/s)	5043006	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
RootComplex Tests, Peak Differential Output Voltage (Non-Transition)(2.5 GT/s)	5013006	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
RootComplex Tests, Peak Differential Output Voltage (Non-Transition)(32.0 GT/s)	5053006	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
RootComplex Tests, Peak Differential Output Voltage (Non-Transition)(5.0 GT/s)	5023006	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
RootComplex Tests, Peak Differential Output Voltage (Non-Transition)(8.0 GT/s)	5033006	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
RootComplex Tests, Peak Differential Output Voltage (Transition)(16.0 GT/s)	5043005	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
RootComplex Tests, Peak Differential Output Voltage (Transition)(2.5 GT/s)	5013005	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
RootComplex Tests, Peak Differential Output Voltage (Transition)(32.0 GT/s)	5053005	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
RootComplex Tests, Peak Differential Output Voltage (Transition)(5.0 GT/s)	5023005	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
RootComplex Tests, Peak Differential Output Voltage (Transition)(8.0 GT/s)	5033005	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
RootComplex Tests, RMS Random Jitter with crosstalk (5.0 GT/s)	5023013	This test verifies RMS Random Jitter, it is informative only.
RootComplex Tests, RMS Random Jitter without crosstalk (5.0 GT/s)	5023014	This test verifies RMS Random Jitter, it is informative only.
RootComplex Tests, Template Tests (16.0 GT/s)	5043002	System Board must meet the System Board Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM).
RootComplex Tests, Template Tests (2.5 GT/s)	5013002	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in PCI Express Card Electromechanical (CEM) Specification, as measured after the connector with an ideal load.
RootComplex Tests, Template Tests (32.0 GT/s)	5053002	System Board must meet the System Board Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM).
RootComplex Tests, Template Tests (5.0 GT/s)	5023002	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in PCI Express Card Electromechanical (CEM) Specification, as measured after the connector with an ideal load.
RootComplex Tests, Template Tests (8.0 GT/s)	5033002	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical Specification (CEM), as measured at the card edge-fingers.
RootComplex Tests, Total Jitter at BER-12 with crosstalk (5.0 GT/s)	5023021	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical (CEM) Specification, as measured after the connector with an ideal load.
RootComplex Tests, Total Jitter at BER-12 without crosstalk (5.0 GT/s)	5023022	System boards must meet the System Board Transmitter Path Compliance Eye Requirements specified in the PCI Express Card Electromechanical (CEM) Specification, as measured after the connector with an ideal load.
RootComplex Tests, Uncorrelated Deterministic Pulse Width Jitter (32.0 GT/s)	5053011	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range. This test required PWJ clock pattern.
RootComplex Tests, Uncorrelated Total Pulse Width Jitter (32.0 GT/s)	5053010	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range. This test required PWJ clock pattern.
RootComplex Tests, Uncorrelated deterministic jitter (32.0 GT/s)	5053013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
RootComplex Tests, Uncorrelated total jitter (32.0 GT/s)	5053012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
RootComplex Tests, Unit Interval (16.0 GT/s)	5043000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
RootComplex Tests, Unit Interval (32.0 GT/s)	5053000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
RootComplex Tests, Unit interval (2.5 GT/s)	5013000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
RootComplex Tests, Unit interval (5.0 GT/s)	5023000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
RootComplex Tests, Unit interval (8.0 GT/s)	5033000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here. The UI range is NOT specified for this test point. It is provided here as informative data only.
Tx, AC common mode voltage - 1.25GHz (LPF) (2.5 GT/s)	5011026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 1.25GHz (LPF) (2.5 GT/s)	6011026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 16GHz (LPF) (32.0 GT/s)	5051026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 16GHz (LPF) (32.0 GT/s)	6051026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 16GHz (LPF) (64.0 GT/s)	6061026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 2.5GHz (LPF) (5.0 GT/s)	4021026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 2.5GHz (LPF) (5.0 GT/s)	5021026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, AC common mode voltage - 2.5GHz (LPF) (5.0 GT/s)	6021026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (16.0 GT/s)	4041027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (16.0 GT/s)	5041027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (16.0 GT/s)	6041027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (32.0 GT/s)	5051027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (32.0 GT/s)	6051027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (5.0 GT/s)	4021027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (5.0 GT/s)	5021027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (5.0 GT/s)	6021027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (64.0 GT/s)	6061027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (8.0 GT/s)	4031027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (8.0 GT/s)	5031027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 30kHz to 500MHz (BPF) (8.0 GT/s)	6031027	This test verify the AC common mode lies in the 0.03-500MHz range, VTX-AC-CM-PP (30kHz - 500MHz) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 4GHz (LPF) (8.0 GT/s)	5031026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 4GHz (LPF) (8.0 GT/s)	6031026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 4GHz (LPF) (8.0 GT/s)	4031026	This test verify the AC common mode, VTX-CM-AC-PP (4GHz LPF) is within the allowed limit as specified in the PCI Express Base Specification. The peak-peak AC Common Mode voltage is reported here.
Tx, AC common mode voltage - 8GHz (LPF) (16.0 GT/s)	4041026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 8GHz (LPF) (16.0 GT/s)	5041026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, AC common mode voltage - 8GHz (LPF) (16.0 GT/s)	6041026	The maximum allowable Tx AC peak-peak common mode voltage is 150mVpp (VTX-AC-CM-PP) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, Absolute delta of DC common mode voltage between D+ and D- (16.0 GT/s)	4041028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (16.0 GT/s)	5041028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Absolute delta of DC common mode voltage between D+ and D- (16.0 GT/s)	6041028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (2.5 GT/s)	5011028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (2.5 GT/s)	6011028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (32.0 GT/s)	5051028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (32.0 GT/s)	6051028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (5.0 GT/s)	5021028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (5.0 GT/s)	6021028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (64.0 GT/s)	6061028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Absolute delta of DC common mode voltage between D+ and D- (8.0 GT/s)	4031028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (8.0 GT/s)	5031028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage between D+ and D- (8.0 GT/s)	6031028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (16.0 GT/s)	4041029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (16.0 GT/s)	5041029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (16.0 GT/s)	6041029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (2.5 GT/s)	5011029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (2.5 GT/s)	6011029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Absolute delta of DC common mode voltage during L0 and Idle (32.0 GT/s)	5051029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (32.0 GT/s)	6051029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (5.0 GT/s)	4021029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (5.0 GT/s)	5021029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (5.0 GT/s)	6021029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (64.0 GT/s)	6061029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (8.0 GT/s)	4031029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Absolute delta of DC common mode voltage during L0 and Idle (8.0 GT/s)	5031029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Absolute delta of DC common mode voltage during L0 and Idle (8.0 GT/s)	6031029	This test verify the absolute delta of DC common mode voltage during L0 and Idle, VTX-CM-DC-ACTIVE-IDLE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute delta of the DC common mode voltage during active and electrical idle.
Tx, Auto Tune Optimized CTLE (52UI Jitter Pattern) (64.0 GT/s)	6061050	This test finds the optimized CTLE in 52UI Jitter pattern.
Tx, Auto Tune Optimized CTLE (PWJ Pattern) (64.0 GT/s)	6061051	This test finds the optimized CTLE in PWJ pattern.
Tx, Avg DC Common Mode Output Voltage (2.5 GT/s)	4011025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, Avg DC common mode voltage (5.0 GT/s)	4021025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC Common Mode Line Delta (2.5 GT/s)	4011028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, DC Common Mode Line Delta (5.0 GT/s)	4021028	This test verify the absolute delta of DC common mode voltage between D+ and D-, VTX-CM-DC-LINE-DELTA is within the allowed limit as specified in the PCI Express Base Specification. This is absolute value of the difference between the average DC value of D+ and the average DC value of D-.
Tx, DC common mode voltage (16.0 GT/s)	4041025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (16.0 GT/s)	5041025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (16.0 GT/s)	6041025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (2.5 GT/s)	5011025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (2.5 GT/s)	6011025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (32.0 GT/s)	5051025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (32.0 GT/s)	6051025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (5.0 GT/s)	5021025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, DC common mode voltage (5.0 GT/s)	6021025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (64.0 GT/s)	6061025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (8.0 GT/s)	4031025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (8.0 GT/s)	5031025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, DC common mode voltage (8.0 GT/s)	6031025	This test verify the DC common mode, VTX-DC-CM is within the allowed limit as specified in the PCI Express Base Specification.
Tx, Data dependent jitter (16.0 GT/s)	4041016	This test verifies that the maximum data dependent jitter, TTX-DDJ is within the allowed range.
Tx, Data dependent jitter (16.0 GT/s)	5041016	This test verifies that the maximum data dependent jitter, TTX-DDJ is within the allowed range.
Tx, Data dependent jitter (2.5 GT/s)	4011016	This test verifies that the maximum data dependent jitter, TTX-DDJ is within the allowed range.
Tx, Data dependent jitter (2.5 GT/s)	5011016	This test verifies that the maximum data dependent jitter, TTX-DDJ is within the allowed range.
Tx, Data dependent jitter (32.0 GT/s)	5051016	This test verifies that the maximum data dependent jitter, TTX-DDJ is within the allowed range.
Tx, Data dependent jitter (5.0 GT/s)	4021016	This test verifies that the maximum data dependent jitter, TTX-DDJ is within the allowed range.
Tx, Data dependent jitter (5.0 GT/s)	5021016	This test verifies that the maximum data dependent jitter, TTX-DDJ is within the allowed range.
Tx, Data dependent jitter (8.0 GT/s)	4031016	This test verifies that the maximum data dependent jitter, TTX-DDJ is within the allowed range.
Tx, Data dependent jitter (8.0 GT/s)	5031016	This test verifies that the maximum data dependent jitter, TTX-DDJ is within the allowed range.
Tx, De-emphasis Preset #0 (16.0 GT/s)	4041100	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #0 (16.0 GT/s)	5041100	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #0 (16.0 GT/s)	6041100	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, De-emphasis Preset #0 (32.0 GT/s)	5051100	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #0 (32.0 GT/s)	6051100	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #0 (8.0 GT/s)	4031100	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #0 (8.0 GT/s)	5031100	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #0 (8.0 GT/s)	6031100	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #1 (16.0 GT/s)	4041101	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #1 (16.0 GT/s)	5041101	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #1 (16.0 GT/s)	6041101	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #1 (32.0 GT/s)	5051101	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #1 (32.0 GT/s)	6051101	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #1 (64.0 GT/s)	6061202	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #1 (8.0 GT/s)	4031101	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #1 (8.0 GT/s)	5031101	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, De-emphasis Preset #1 (8.0 GT/s)	6031101	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #10 (16.0 GT/s)	4041111	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #10 (16.0 GT/s)	5041111	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #10 (16.0 GT/s)	6041111	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #10 (32.0 GT/s)	5051111	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #10 (32.0 GT/s)	6051111	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #10 (64.0 GT/s)	6061229	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #10 (8.0 GT/s)	4031111	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #10 (8.0 GT/s)	5031111	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #10 (8.0 GT/s)	6031111	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #2 (16.0 GT/s)	4041102	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #2 (16.0 GT/s)	5041102	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #2 (16.0 GT/s)	6041102	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, De-emphasis Preset #2 (32.0 GT/s)	5051102	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #2 (32.0 GT/s)	6051102	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #2 (64.0 GT/s)	6061205	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #2 (8.0 GT/s)	4031102	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #2 (8.0 GT/s)	5031102	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #2 (8.0 GT/s)	6031102	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #3 (16.0 GT/s)	4041103	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #3 (16.0 GT/s)	5041103	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #3 (16.0 GT/s)	6041103	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #3 (32.0 GT/s)	5051103	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #3 (32.0 GT/s)	6051103	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #3 (64.0 GT/s)	6061208	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #3 (8.0 GT/s)	4031103	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, De-emphasis Preset #3 (8.0 GT/s)	5031103	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #3 (8.0 GT/s)	6031103	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #4 (64.0 GT/s)	6061211	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q4 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #5 (32.0 GT/s)	5051116	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #5 (32.0 GT/s)	6051116	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #5 (64.0 GT/s)	6061214	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #6 (32.0 GT/s)	5051117	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #6 (32.0 GT/s)	6051117	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #6 (64.0 GT/s)	6061217	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #7 (16.0 GT/s)	4041107	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #7 (16.0 GT/s)	5041107	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #7 (16.0 GT/s)	6041107	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #7 (32.0 GT/s)	5051107	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, De-emphasis Preset #7 (32.0 GT/s)	6051107	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #7 (64.0 GT/s)	6061220	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #7 (8.0 GT/s)	4031107	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #7 (8.0 GT/s)	5031107	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #7 (8.0 GT/s)	6031107	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #8 (16.0 GT/s)	4041109	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #8 (16.0 GT/s)	5041109	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #8 (16.0 GT/s)	6041109	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #8 (32.0 GT/s)	5051109	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #8 (32.0 GT/s)	6051109	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #8 (64.0 GT/s)	6061223	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #8 (8.0 GT/s)	4031109	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #8 (8.0 GT/s)	5031109	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, De-emphasis Preset #8 (8.0 GT/s)	6031109	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #9 (32.0 GT/s)	5051118	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #9 (32.0 GT/s)	6051118	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, De-emphasis Preset #9 (64.0 GT/s)	6061226	The purpose of this test is to verify that the De-emphasis(dB) of the transmitter Tx at preset number Q9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Deemphasized Voltage Ratio (2.5 GT/s)	4011001	The de-emphasis level is measured as the ratio of the non-transition voltage to transition voltage, $V_{TX-DE-RATIO} = -20\log_{10}(V_{TX-DIFF-PP}/V_{TX-DE-EMPH-PP})$. This measurement is for de-emphasis level settings of -3.5dB.
Tx, Deemphasized Voltage Ratio (2.5 GT/s)	5011001	The de-emphasis level is measured as the ratio of the non-transition voltage to transition voltage, $V_{TX-DE-RATIO} = -20\log_{10}(V_{TX-DIFF-PP}/V_{TX-DE-EMPH-PP})$. This measurement is for de-emphasis level settings of -3.5dB.
Tx, Deemphasized Voltage Ratio (2.5 GT/s)	6011001	The de-emphasis level is measured as the ratio of the non-transition voltage to transition voltage, $V_{TX-DE-RATIO} = -20\log_{10}(V_{TX-DIFF-PP}/V_{TX-DE-EMPH-PP})$. This measurement is for de-emphasis level settings of -3.5dB.
Tx, Deemphasized Voltage Ratio -3.5dB (5.0 GT/s)	4021001	The de-emphasis level is measured as the ratio of the non-transition voltage to transition voltage, $V_{TX-DE-RATIO} = -20\log_{10}(V_{TX-DIFF-PP}/V_{TX-DE-EMPH-PP})$. This measurement is for de-emphasis level settings of -3.5dB.
Tx, Deemphasized Voltage Ratio -3.5dB (5.0 GT/s)	5021001	The de-emphasis level is measured as the ratio of the non-transition voltage to transition voltage, $V_{TX-DE-RATIO} = -20\log_{10}(V_{TX-DIFF-PP}/V_{TX-DE-EMPH-PP})$. This measurement is for de-emphasis level settings of -3.5dB.
Tx, Deemphasized Voltage Ratio -3.5dB (5.0 GT/s)	6021001	The de-emphasis level is measured as the ratio of the non-transition voltage to transition voltage, $V_{TX-DE-RATIO} = -20\log_{10}(V_{TX-DIFF-PP}/V_{TX-DE-EMPH-PP})$. This measurement is for de-emphasis level settings of -3.5dB.
Tx, Deemphasized Voltage Ratio -6.0dB (5.0 GT/s)	4021002	The de-emphasis level is measured as the ratio of the non-transition voltage to transition voltage, $V_{TX-DE-RATIO} = -20\log_{10}(V_{TX-DIFF-PP}/V_{TX-DE-EMPH-PP})$. This measurement is for de-emphasis level settings of -6dB.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Deemphasized Voltage Ratio -6.0dB (5.0 GT/s)	5021002	The de-emphasis level is measured as the ratio of the non-transition voltage to transition voltage, $V_{TX-DE-RATIO} = -20\log_{10}(V_{TX-DIFF-PP}/V_{TX-DE-EMPH-PP})$. This measurement is for de-emphasis level settings of -6dB.
Tx, Deemphasized Voltage Ratio -6.0dB (5.0 GT/s)	6021002	The de-emphasis level is measured as the ratio of the non-transition voltage to transition voltage, $V_{TX-DE-RATIO} = -20\log_{10}(V_{TX-DIFF-PP}/V_{TX-DE-EMPH-PP})$. This measurement is for de-emphasis level settings of -6dB.
Tx, Deterministic DjDD uncorrelated PWJ (16.0 GT/s)	4041015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range. This test required PWJ clock pattern.
Tx, Deterministic DjDD uncorrelated PWJ (16.0 GT/s)	5041015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range. This test required PWJ clock pattern.
Tx, Deterministic DjDD uncorrelated PWJ (16.0 GT/s)	6041015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range. This test required PWJ clock pattern.
Tx, Deterministic DjDD uncorrelated PWJ (2.5 GT/s)	4011015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range.
Tx, Deterministic DjDD uncorrelated PWJ (32.0 GT/s)	5051015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range. This test required PWJ clock pattern.
Tx, Deterministic DjDD uncorrelated PWJ (32.0 GT/s)	6051015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range. This test required PWJ clock pattern.
Tx, Deterministic DjDD uncorrelated PWJ (5.0 GT/s)	4021015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range.
Tx, Deterministic DjDD uncorrelated PWJ (5.0 GT/s)	5021015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range.
Tx, Deterministic DjDD uncorrelated PWJ (5.0 GT/s)	6021015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range.
Tx, Deterministic DjDD uncorrelated PWJ (64.0 GT/s)	6061015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range. This test required PWJ clock pattern.
Tx, Deterministic DjDD uncorrelated PWJ (8.0 GT/s)	4031015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range.
Tx, Deterministic DjDD uncorrelated PWJ (8.0 GT/s)	5031015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range.
Tx, Deterministic DjDD uncorrelated PWJ (8.0 GT/s)	6031015	This test verifies that the maximum deterministic DjDD uncorrelated PWJ TTX-UPW-DJDD is within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Eye-Width (2.5 GT/s)	4011006	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [peak-to-peak jitter].
Tx, Eye-Width (5.0 GT/s)	4021006	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [peak-to-peak jitter].
Tx, Eye-Width (Low Power) (2.5 GT/s)	4011009	This test measures the eye-width of the compliance eye. The eye-width is computed as the [mean unit interval] - [peak-to-peak jitter].
Tx, Full swing Tx voltage with no TxEQ (16.0 GT/s)	4041010	This test verifies that the full swing Tx voltage with no equalization VTX-DIFF-PP is within the allowed range. This test required Preset 04.
Tx, Full swing Tx voltage with no TxEQ (16.0 GT/s)	5041010	This test verifies that the full swing Tx voltage with no equalization VTX-DIFF-PP is within the allowed range. This test required Preset 04.
Tx, Full swing Tx voltage with no TxEQ (16.0 GT/s)	6041010	This test verifies that the full swing Tx voltage with no equalization VTX-DIFF-PP is within the allowed range. This test required Preset 04.
Tx, Full swing Tx voltage with no TxEQ (32.0 GT/s)	5051010	This test verifies that the full swing Tx voltage with no equalization VTX-DIFF-PP is within the allowed range. This test required Preset 04.
Tx, Full swing Tx voltage with no TxEQ (32.0 GT/s)	6051010	This test verifies that the full swing Tx voltage with no equalization VTX-DIFF-PP is within the allowed range. This test required Preset 04.
Tx, Full swing Tx voltage with no TxEQ (64.0 GT/s)	6061010	This test verifies that the full swing Tx voltage with no equalization VTX-DIFF-PP is within the allowed range. This test required Preset 00.
Tx, Full swing Tx voltage with no TxEQ (8.0 GT/s)	4031010	This test verifies that the full swing Tx voltage with no equalization VTX-DIFF-PP is within the allowed range. This test required Preset 04.
Tx, Full swing Tx voltage with no TxEQ (8.0 GT/s)	5031010	This test verifies that the full swing Tx voltage with no equalization VTX-DIFF-PP is within the allowed range. This test required Preset 04.
Tx, Full swing Tx voltage with no TxEQ (8.0 GT/s)	6031010	This test verifies that the full swing Tx voltage with no equalization VTX-DIFF-PP is within the allowed range. This test required Preset 04.
Tx, Level Separation Mismatch Ratio (64.0 GT/s)	6061046	This test verifies that the Level Separation Mismatch Ratio is within the allowed range. This test required Preset 00.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Maximum nominal Tx boost ratio for full swing (16.0 GT/s)	6041040	This test verifies that the maximum nominal Tx boost ratio for full swing, VTX-BOOST-FS is within the allowed range. This test required Preset 10.
Tx, Maximum nominal Tx boost ratio for full swing (16.0 GT/s)	4041040	This test verifies that the maximum nominal Tx boost ratio for full swing, VTX-BOOST-RS is within the allowed range. This test required Preset 10.
Tx, Maximum nominal Tx boost ratio for full swing (16.0 GT/s)	5041040	This test verifies that the maximum nominal Tx boost ratio for full swing, VTX-BOOST-RS is within the allowed range. This test required Preset 10.
Tx, Maximum nominal Tx boost ratio for full swing (32.0 GT/s)	6051040	This test verifies that the maximum nominal Tx boost ratio for full swing, VTX-BOOST-FS is within the allowed range. This test required Preset 10.
Tx, Maximum nominal Tx boost ratio for full swing (32.0 GT/s)	5051040	This test verifies that the maximum nominal Tx boost ratio for full swing, VTX-BOOST-RS is within the allowed range. This test required Preset 10.
Tx, Maximum nominal Tx boost ratio for full swing (64.0 GT/s)	6061040	This test verifies that the maximum nominal Tx boost ratio for full swing, VTX-BOOST-FS is within the allowed range. This test required Preset Q10.
Tx, Maximum nominal Tx boost ratio for full swing (8.0 GT/s)	4031040	This test verifies that the maximum nominal Tx boost ratio for full swing, VTX-BOOST-RS is within the allowed range. This test required Preset 10.
Tx, Maximum nominal Tx boost ratio for full swing (8.0 GT/s)	5031040	This test verifies that the maximum nominal Tx boost ratio for full swing, VTX-BOOST-RS is within the allowed range. This test required Preset 10.
Tx, Maximum nominal Tx boost ratio for full swing (8.0 GT/s)	6031040	This test verifies that the maximum nominal Tx boost ratio for full swing, VTX-BOOST-RS is within the allowed range. This test required Preset 10.
Tx, Maximum nominal Tx boost ratio for reduced swing (16.0 GT/s)	4041039	This test verifies that the maximum nominal Tx boost ratio for reduced swing, VTX-BOOST-RS is within the allowed range. This test required Preset 01.
Tx, Maximum nominal Tx boost ratio for reduced swing (16.0 GT/s)	5041039	This test verifies that the maximum nominal Tx boost ratio for reduced swing, VTX-BOOST-RS is within the allowed range. This test required Preset 01.
Tx, Maximum nominal Tx boost ratio for reduced swing (16.0 GT/s)	6041039	This test verifies that the maximum nominal Tx boost ratio for reduced swing, VTX-BOOST-RS is within the allowed range. This test required Preset 01.
Tx, Maximum nominal Tx boost ratio for reduced swing (32.0 GT/s)	5051039	This test verifies that the maximum nominal Tx boost ratio for reduced swing, VTX-BOOST-RS is within the allowed range. This test required Preset 01.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Maximum nominal Tx boost ratio for reduced swing (32.0 GT/s)	6051039	This test verifies that the maximum nominal Tx boost ratio for reduced swing, VTX-BOOST-RS is within the allowed range. This test required Preset 01.
Tx, Maximum nominal Tx boost ratio for reduced swing (64.0 GT/s)	6061039	This test verifies that the maximum nominal Tx boost ratio for reduced swing, VTX-BOOST-RS is within the allowed range. This test required Preset Q4.
Tx, Maximum nominal Tx boost ratio for reduced swing (8.0 GT/s)	4031039	This test verifies that the maximum nominal Tx boost ratio for reduced swing, VTX-BOOST-RS is within the allowed range. This test required Preset 01.
Tx, Maximum nominal Tx boost ratio for reduced swing (8.0 GT/s)	5031039	This test verifies that the maximum nominal Tx boost ratio for reduced swing, VTX-BOOST-RS is within the allowed range. This test required Preset 01.
Tx, Maximum nominal Tx boost ratio for reduced swing (8.0 GT/s)	6031039	This test verifies that the maximum nominal Tx boost ratio for reduced swing, VTX-BOOST-RS is within the allowed range. This test required Preset 01.
Tx, Median to Max Jitter (2.5 GT/s)	4011005	This test measures the maximum time between the jitter median and maximum deviation from the median.
Tx, Median to Max Jitter (Low Power) (2.5 GT/s)	4011008	This test measures the maximum time between the jitter median and maximum deviation from the median.
Tx, Min swing during EIEOS for full swing (16.0 GT/s)	4041019	This test verifies that the minimum swing during EIEOS for full swing VTX-EIEOS-FS is within the allowed range.
Tx, Min swing during EIEOS for full swing (16.0 GT/s)	5041019	This test verifies that the minimum swing during EIEOS for full swing VTX-EIEOS-FS is within the allowed range.
Tx, Min swing during EIEOS for full swing (16.0 GT/s)	6041019	This test verifies that the minimum swing during EIEOS for full swing VTX-EIEOS-FS is within the allowed range.
Tx, Min swing during EIEOS for full swing (32.0 GT/s)	5051019	This test verifies that the minimum swing during EIEOS for full swing VTX-EIEOS-FS is within the allowed range.
Tx, Min swing during EIEOS for full swing (32.0 GT/s)	6051019	This test verifies that the minimum swing during EIEOS for full swing VTX-EIEOS-FS is within the allowed range.
Tx, Min swing during EIEOS for full swing (64.0 GT/s)	6061019	This test verifies that the minimum swing during EIEOS for full swing VTX-EIEOS-FS is within the allowed range. This test required Preset 10.
Tx, Min swing during EIEOS for full swing (8.0 GT/s)	4031019	This test verifies that the minimum swing during EIEOS for full swing VTX-EIEOS-FS is within the allowed range.
Tx, Min swing during EIEOS for full swing (8.0 GT/s)	5031019	This test verifies that the minimum swing during EIEOS for full swing VTX-EIEOS-FS is within the allowed range.
Tx, Min swing during EIEOS for full swing (8.0 GT/s)	6031019	This test verifies that the minimum swing during EIEOS for full swing VTX-EIEOS-FS is within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Min swing during EIEOS for reduced swing (16.0 GT/s, Low Power)	4041020	This test verifies that the minimum swing during EIEOS for reduced swing VTX-EIEOS-RS is within the allowed range. This test required Preset 01.
Tx, Min swing during EIEOS for reduced swing (16.0 GT/s, Low Power)	5041020	This test verifies that the minimum swing during EIEOS for reduced swing VTX-EIEOS-RS is within the allowed range. This test required Preset 01.
Tx, Min swing during EIEOS for reduced swing (16.0 GT/s, Low Power)	6041020	This test verifies that the minimum swing during EIEOS for reduced swing VTX-EIEOS-RS is within the allowed range. This test required Preset 01.
Tx, Min swing during EIEOS for reduced swing (32.0 GT/s, Low Power)	5051020	This test verifies that the minimum swing during EIEOS for reduced swing VTX-EIEOS-RS is within the allowed range. This test required Preset 01.
Tx, Min swing during EIEOS for reduced swing (32.0 GT/s, Low Power)	6051020	This test verifies that the minimum swing during EIEOS for reduced swing VTX-EIEOS-RS is within the allowed range. This test required Preset 01.
Tx, Min swing during EIEOS for reduced swing (64.0 GT/s, Low Power)	6061020	This test verifies that the minimum swing during EIEOS for reduced swing VTX-EIEOS-RS is within the allowed range. This test required Preset 04.
Tx, Min swing during EIEOS for reduced swing (8.0 GT/s, Low Power)	4031020	This test verifies that the minimum swing during EIEOS for reduced swing VTX-EIEOS-RS is within the allowed range. This test required Preset 01.
Tx, Min swing during EIEOS for reduced swing (8.0 GT/s, Low Power)	5031020	This test verifies that the minimum swing during EIEOS for reduced swing VTX-EIEOS-RS is within the allowed range. This test required Preset 01.
Tx, Min swing during EIEOS for reduced swing (8.0 GT/s, Low Power)	6031020	This test verifies that the minimum swing during EIEOS for reduced swing VTX-EIEOS-RS is within the allowed range. This test required Preset 01.
Tx, Peak Differential Output Voltage (Non-Transition)(2.5 GT/s)	4011035	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
Tx, Peak Differential Output Voltage (Non-Transition)(2.5 GT/s)	5011035	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
Tx, Peak Differential Output Voltage (Non-Transition)(2.5 GT/s)	6011035	This test verifies that the Peak Differential Output Voltage (Non-Transition) is within the allowed range.
Tx, Peak Differential Output Voltage (Non-Transition)(2.5 GT/s, Low Power)	4011036	This test verifies that the Peak Differential Output Voltage (Non-Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Non-Transition)(2.5 GT/s, Low Power)	5011036	This test verifies that the Peak Differential Output Voltage (Non-Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Non-Transition)(2.5 GT/s, Low Power)	6011036	This test verifies that the Peak Differential Output Voltage (Non-Transition) (Low Power) is within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Peak Differential Output Voltage (Non-Transition)(5.0 GT/s, Low Power)	4021036	This test verifies that the Peak Differential Output Voltage (Non-Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Non-Transition)(5.0 GT/s, Low Power)	5021036	This test verifies that the Peak Differential Output Voltage (Non-Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Non-Transition)(5.0 GT/s, Low Power)	6021036	This test verifies that the Peak Differential Output Voltage (Non-Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Transition) (5.0 GT/s, Low Power)	4021011	This test verifies that the Peak Differential Output Voltage (Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Transition) (5.0 GT/s, Low Power)	5021011	This test verifies that the Peak Differential Output Voltage (Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Transition) (5.0 GT/s, Low Power)	6021011	This test verifies that the Peak Differential Output Voltage (Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Transition)(2.5 GT/s)	4011010	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
Tx, Peak Differential Output Voltage (Transition)(2.5 GT/s)	5011010	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
Tx, Peak Differential Output Voltage (Transition)(2.5 GT/s)	6011010	This test verifies that the Peak Differential Output Voltage (Transition) is within the allowed range.
Tx, Peak Differential Output Voltage (Transition)(2.5 GT/s, Low Power)	4011011	This test verifies that the Peak Differential Output Voltage (Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Transition)(2.5 GT/s, Low Power)	5011011	This test verifies that the Peak Differential Output Voltage (Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage (Transition)(2.5 GT/s, Low Power)	6011011	This test verifies that the Peak Differential Output Voltage (Transition) (Low Power) is within the allowed range.
Tx, Peak Differential Output Voltage -3.5dB (Non-Transition)(5.0 GT/s)	4021035	This test verifies that the Peak Differential Output Voltage -3.5dB (Non-Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -3.5dB (Non-Transition)(5.0 GT/s)	5021035	This test verifies that the Peak Differential Output Voltage -3.5dB (Non-Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -3.5dB (Non-Transition)(5.0 GT/s)	6021035	This test verifies that the Peak Differential Output Voltage -3.5dB (Non-Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -3.5dB (Transition) (5.0 GT/s)	4021010	This test verifies that the Peak Differential Output Voltage -3.5dB (Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -3.5dB (Transition)(5.0 GT/s)	5021010	This test verifies that the Peak Differential Output Voltage -3.5dB (Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -3.5dB (Transition)(5.0 GT/s)	6021010	This test verifies that the Peak Differential Output Voltage -3.5dB (Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -6.0dB (Non-Transition)(5.0 GT/s)	4021038	This test verifies that the Peak Differential Output Voltage -6.0dB (Non-Transition) is within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Peak Differential Output Voltage -6.0dB (Non-Transition)(5.0 GT/s)	5021038	This test verifies that the Peak Differential Output Voltage -6.0dB (Non-Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -6.0dB (Non-Transition)(5.0 GT/s)	6021038	This test verifies that the Peak Differential Output Voltage -6.0dB (Non-Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -6.0dB (Transition) (5.0 GT/s)	4021037	This test verifies that the Peak Differential Output Voltage -6.0dB (Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -6.0dB (Transition)(5.0 GT/s)	5021037	This test verifies that the Peak Differential Output Voltage -6.0dB (Transition) is within the allowed range.
Tx, Peak Differential Output Voltage -6.0dB (Transition)(5.0 GT/s)	6021037	This test verifies that the Peak Differential Output Voltage -6.0dB (Transition) is within the allowed range.
Tx, Preshoot 1 Preset #1 (64.0 GT/s)	6061201	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 1 Preset #10 (64.0 GT/s)	6061228	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 1 Preset #2 (64.0 GT/s)	6061204	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 1 Preset #3 (64.0 GT/s)	6061207	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 1 Preset #4 (64.0 GT/s)	6061210	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q4 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 1 Preset #5 (64.0 GT/s)	6061213	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 1 Preset #6 (64.0 GT/s)	6061216	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 1 Preset #7 (64.0 GT/s)	6061219	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 1 Preset #8 (64.0 GT/s)	6061222	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 1 Preset #9 (64.0 GT/s)	6061225	The purpose of this test is to verify that the Preshoot 1(dB) of the transmitter Tx at preset number Q9 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Preshoot 2 Preset #1 (64.0 GT/s)	6061200	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 2 Preset #10 (64.0 GT/s)	6061227	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 2 Preset #2 (64.0 GT/s)	6061203	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 2 Preset #3 (64.0 GT/s)	6061206	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 2 Preset #4 (64.0 GT/s)	6061209	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q4 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 2 Preset #5 (64.0 GT/s)	6061212	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 2 Preset #6 (64.0 GT/s)	6061215	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 2 Preset #7 (64.0 GT/s)	6061218	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 2 Preset #8 (64.0 GT/s)	6061221	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot 2 Preset #9 (64.0 GT/s)	6061224	The purpose of this test is to verify that the Preshoot 2(dB) of the transmitter Tx at preset number Q9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #0 (32.0 GT/s)	5051112	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #0 (32.0 GT/s)	6051112	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P0 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #1 (32.0 GT/s)	5051113	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Preshoot Preset #1 (32.0 GT/s)	6051113	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P1 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #10 (32.0 GT/s)	5051119	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #10 (32.0 GT/s)	6051119	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P10 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #2 (32.0 GT/s)	5051114	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #2 (32.0 GT/s)	6051114	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P2 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #3 (32.0 GT/s)	5051115	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #3 (32.0 GT/s)	6051115	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P3 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #5 (16.0 GT/s)	4041104	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #5 (16.0 GT/s)	5041104	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #5 (16.0 GT/s)	6041104	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #5 (32.0 GT/s)	5051104	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #5 (32.0 GT/s)	6051104	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #5 (8.0 GT/s)	4031104	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Preshoot Preset #5 (8.0 GT/s)	5031104	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #5 (8.0 GT/s)	6031104	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P5 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #6 (16.0 GT/s)	4041105	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #6 (16.0 GT/s)	5041105	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #6 (16.0 GT/s)	6041105	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #6 (32.0 GT/s)	5051105	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #6 (32.0 GT/s)	6051105	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #6 (8.0 GT/s)	4031105	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #6 (8.0 GT/s)	5031105	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #6 (8.0 GT/s)	6031105	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P6 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #7 (16.0 GT/s)	4041106	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #7 (16.0 GT/s)	5041106	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #7 (16.0 GT/s)	6041106	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Preshoot Preset #7 (32.0 GT/s)	5051106	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #7 (32.0 GT/s)	6051106	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #7 (8.0 GT/s)	4031106	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #7 (8.0 GT/s)	5031106	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #7 (8.0 GT/s)	6031106	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P7 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #8 (16.0 GT/s)	4041108	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #8 (16.0 GT/s)	5041108	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #8 (16.0 GT/s)	6041108	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #8 (32.0 GT/s)	5051108	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #8 (32.0 GT/s)	6051108	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #8 (8.0 GT/s)	4031108	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #8 (8.0 GT/s)	5031108	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #8 (8.0 GT/s)	6031108	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P8 is within the conformance limits specified in the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Preshoot Preset #9 (16.0 GT/s)	4041110	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #9 (16.0 GT/s)	5041110	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #9 (16.0 GT/s)	6041110	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #9 (32.0 GT/s)	5051110	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #9 (32.0 GT/s)	6051110	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #9 (8.0 GT/s)	4031110	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #9 (8.0 GT/s)	5031110	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Preshoot Preset #9 (8.0 GT/s)	6031110	The purpose of this test is to verify that the Preshoot(dB) of the transmitter Tx at preset number P9 is within the conformance limits specified in the PCI Express Base Specification.
Tx, Pseudo package loss, Non-Root Device (32.0 GT/s)	5051018	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Non-Root Device (32.0 GT/s)	6051018	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Non-Root Device (64.0 GT/s)	6061018	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 00.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Pseudo package loss, Non-Root Device (8.0 GT/s)	4031018	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Non-Root Device (8.0 GT/s)	5031018	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Non-Root Device (8.0 GT/s)	6031018	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Non-Root Device, Captive Channel (16.0 GT/s)	4041018	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Non-Root Device, Captive Channel (16.0 GT/s)	5041018	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Non-Root Device, Captive Channel (16.0 GT/s)	6041018	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Non-Root Device, No Captive Channel (16.0 GT/s)	4041031	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Non-Root Device, No Captive Channel (16.0 GT/s)	5041031	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Pseudo package loss, Non-Root Device, No Captive Channel (16.0 GT/s)	6041031	This test verifies that the maximum pseudo package loss for all devices without root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Root Device (16.0 GT/s)	5041030	This test verifies that the maximum pseudo package loss for all devices with root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Root Device (16.0 GT/s)	6041030	This test verifies that the maximum pseudo package loss for all devices with root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Root Device (16.0 GT/s)	4041030	This test verifies that the maximum pseudo package loss for all devices with root ports, ps21TX is within the allowed range. This test required Preset 04.
Tx, Pseudo package loss, Root Device (32.0 GT/s)	5051030	This test verifies that the maximum pseudo package loss for all devices with root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Root Device (32.0 GT/s)	6051030	This test verifies that the maximum pseudo package loss for all devices with root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Root Device (64.0 GT/s)	6061030	This test verifies that the maximum pseudo package loss for all devices with root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 00.
Tx, Pseudo package loss, Root Device (8.0 GT/s)	5031030	This test verifies that the maximum pseudo package loss for all devices with root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.
Tx, Pseudo package loss, Root Device (8.0 GT/s)	6031030	This test verifies that the maximum pseudo package loss for all devices with root ports, ps21TX is within the allowed range. Pseudo package loss is calculated as ratio of voltage swing of a 1010 pattern against a 64-zeroes/64-ones pattern as described in Section 8.3.3.11. This test required Preset 04.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Pseudo package loss, Root Device (8.0 GT/s)	4031030	This test verifies that the maximum pseudo package loss of all devices with root ports, ps21TX is within the allowed range. This test required Preset 04.
Tx, RMS AC Peak Common Mode Output Voltage (2.5 GT/s)	4011033	The maximum allowable RMS AC (>30Khz) common mode voltage is 20mV (Vtx-cm-acp) as measured at the package pins of the transmitter using the Compliance Test and Measurement Load.
Tx, Random jitter (16.0 GT/s)	4041017	This test verifies random jitter, it is informative only.
Tx, Random jitter (16.0 GT/s)	5041017	This test verifies random jitter, it is informative only.
Tx, Random jitter (16.0 GT/s)	6041017	This test verifies random jitter, it is informative only.
Tx, Random jitter (2.5 GT/s)	4011017	This test verifies random jitter, it is informative only.
Tx, Random jitter (32.0 GT/s)	5051017	This test verifies random jitter, it is informative only.
Tx, Random jitter (32.0 GT/s)	6051017	This test verifies random jitter, it is informative only.
Tx, Random jitter (5.0 GT/s)	4021017	This test verifies random jitter, it is informative only.
Tx, Random jitter (5.0 GT/s)	5021017	This test verifies random jitter, it is informative only.
Tx, Random jitter (5.0 GT/s)	6021017	This test verifies random jitter, it is informative only.
Tx, Random jitter (64.0 GT/s)	6061017	This test verifies random jitter, it is informative only.
Tx, Random jitter (8.0 GT/s)	4031017	This test verifies random jitter, it is informative only.
Tx, Random jitter (8.0 GT/s)	5031017	This test verifies random jitter, it is informative only.
Tx, Random jitter (8.0 GT/s)	6031017	This test verifies random jitter, it is informative only.
Tx, Reduced swing Tx voltage with no TxEQ (16.0 GT/s, Low Power)	4041011	This test verifies that the reduced swing Tx output voltage with no equalization VTX-DIFF-PP-LOW is within the allowed range. This test required Preset 04.
Tx, Reduced swing Tx voltage with no TxEQ (16.0 GT/s, Low Power)	5041011	This test verifies that the reduced swing Tx output voltage with no equalization VTX-DIFF-PP-LOW is within the allowed range. This test required Preset 04.
Tx, Reduced swing Tx voltage with no TxEQ (16.0 GT/s, Low Power)	6041011	This test verifies that the reduced swing Tx output voltage with no equalization VTX-DIFF-PP-LOW is within the allowed range. This test required Preset 04.
Tx, Reduced swing Tx voltage with no TxEQ (32.0 GT/s, Low Power)	5051011	This test verifies that the reduced swing Tx output voltage with no equalization VTX-DIFF-PP-LOW is within the allowed range. This test required Preset 04.
Tx, Reduced swing Tx voltage with no TxEQ (32.0 GT/s, Low Power)	6051011	This test verifies that the reduced swing Tx output voltage with no equalization VTX-DIFF-PP-LOW is within the allowed range. This test required Preset 04.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Reduced swing Tx voltage with no TxEQ (64.0 GT/s, Low Power)	6061011	This test verifies that the reduced swing Tx output voltage with no equalization VTX-DIFF-PP-LOW is within the allowed range. This test required Preset 00.
Tx, Reduced swing Tx voltage with no TxEQ (8.0 GT/s, Low Power)	4031011	This test verifies that the reduced swing Tx output voltage with no equalization VTX-DIFF-PP-LOW is within the allowed range. This test required Preset 04.
Tx, Reduced swing Tx voltage with no TxEQ (8.0 GT/s, Low Power)	5031011	This test verifies that the reduced swing Tx output voltage with no equalization VTX-DIFF-PP-LOW is within the allowed range. This test required Preset 04.
Tx, Reduced swing Tx voltage with no TxEQ (8.0 GT/s, Low Power)	6031011	This test verifies that the reduced swing Tx output voltage with no equalization VTX-DIFF-PP-LOW is within the allowed range. This test required Preset 04.
Tx, SSC Df/Dt (Max)(PCIE 4.0 16.0GT/s)	4041024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 4.0 8.0GT/s)	4031024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 5.0 16.0GT/s)	5041024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 5.0 2.5GT/s)	5011024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 5.0 32.0GT/s)	5051024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 5.0 5.0GT/s)	5021024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 5.0 8.0GT/s)	5031024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 6.0 16.0GT/s)	6041024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 6.0 2.5GT/s)	6011024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 6.0 32.0GT/s)	6051024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 6.0 5.0GT/s)	6021024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 6.0 64.0GT/s)	6061024	This test verifies that the SSC maximum slew rate is within the allowed range.
Tx, SSC Df/Dt (Max)(PCIE 6.0 8.0GT/s)	6031024	This test verifies that the SSC maximum slew rate is within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, SSC Modulation Frequency (PCIE 4.0 16.0GT/s)	4041021	This test verifies that the SSC frequency range is in the allowable range. This test required Preset 04.
Tx, SSC Modulation Frequency (PCIE 4.0 8.0GT/s)	4031021	This test verifies that the SSC frequency range is in the allowable range. This test required Preset 04.
Tx, SSC Modulation Frequency (PCIE 5.0 16.0GT/s)	5041021	This test verifies that the SSC frequency range is in the allowable range. This test required Preset 04.
Tx, SSC Modulation Frequency (PCIE 5.0 2.5GT/s)	5011021	This test verifies that the SSC frequency range is in the allowable range.
Tx, SSC Modulation Frequency (PCIE 5.0 32.0GT/s)	5051021	This test verifies that the SSC frequency range is in the allowable range. This test required Preset 04.
Tx, SSC Modulation Frequency (PCIE 5.0 5.0GT/s)	5021021	This test verifies that the SSC frequency range is in the allowable range.
Tx, SSC Modulation Frequency (PCIE 5.0 8.0GT/s)	5031021	This test verifies that the SSC frequency range is in the allowable range. This test required Preset 04.
Tx, SSC Modulation Frequency (PCIE 6.0 16.0GT/s)	6041021	This test verifies that the SSC frequency range is in the allowable range. This test required Preset 04.
Tx, SSC Modulation Frequency (PCIE 6.0 2.5GT/s)	6011021	This test verifies that the SSC frequency range is in the allowable range.
Tx, SSC Modulation Frequency (PCIE 6.0 32.0GT/s)	6051021	This test verifies that the SSC frequency range is in the allowable range. This test required Preset 04.
Tx, SSC Modulation Frequency (PCIE 6.0 5.0GT/s)	6021021	This test verifies that the SSC frequency range is in the allowable range.
Tx, SSC Modulation Frequency (PCIE 6.0 64.0GT/s)	6061021	This test verifies that the SSC frequency range is in the allowable range.
Tx, SSC Modulation Frequency (PCIE 6.0 8.0GT/s)	6031021	This test verifies that the SSC frequency range is in the allowable range. This test required Preset 04.
Tx, SSC Peak Deviation (Max) (PCIE 4.0 16.0GT/s)	4041022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 4.0 8.0GT/s)	4031022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 5.0 16.0GT/s)	5041022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 5.0 2.5GT/s)	5011022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 5.0 32.0GT/s)	5051022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 5.0 5.0GT/s)	5021022	This test verifies that the SSC maximum deviation within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, SSC Peak Deviation (Max) (PCIE 5.0 8.0GT/s)	5031022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 6.0 16.0GT/s)	6041022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 6.0 2.5GT/s)	6011022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 6.0 32.0GT/s)	6051022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 6.0 5.0GT/s)	6021022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 6.0 64.0GT/s)	6061022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Max) (PCIE 6.0 8.0GT/s)	6031022	This test verifies that the SSC maximum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 4.0 16.0GT/s)	4041023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 4.0 8.0GT/s)	4031023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 5.0 16.0GT/s)	5041023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 5.0 2.5GT/s)	5011023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 5.0 32.0GT/s)	5051023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 5.0 5.0GT/s)	5021023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 5.0 8.0GT/s)	5031023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 6.0 16.0GT/s)	6041023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 6.0 2.5GT/s)	6011023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 6.0 32.0GT/s)	6051023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 6.0 5.0GT/s)	6021023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, SSC Peak Deviation (Min) (PCIE 6.0 64.0GT/s)	6061023	This test verifies that the SSC minimum deviation within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, SSC Peak Deviation (Min) (PCIe 6.0 8.0GT/s)	6031023	This test verifies that the SSC minimum deviation within the allowed range.
Tx, Signal-to-Noise-Distortion Ratio (64.0 GT/s)	6061045	This test verifies that the Signal-to-Noise-Distortion Ratio is within the allowed range. This test required Preset 00.
Tx, Template Tests (2.5 GT/s)	4011004	This test verifies transmitter eye diagram, it is informative only.
Tx, Template Tests (Low Power) (2.5 GT/s)	4011007	This test verifies transmitter eye diagram, it is informative only.
Tx, Template Tests (Low Power) (5.0 GT/s)	4021007	This test verifies transmitter eye diagram, it is informative only.
Tx, Template Tests -3.5dB (5.0 GT/s)	4021004	This test verifies transmitter eye diagram, it is informative only.
Tx, Template Tests -6.0dB (5.0 GT/s)	4021032	This test verifies transmitter eye diagram, it is informative only.
Tx, Total uncorrelated PWJ (16.0 GT/s)	4041014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range. This test required PWJ clock pattern.
Tx, Total uncorrelated PWJ (16.0 GT/s)	5041014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range. This test required PWJ clock pattern.
Tx, Total uncorrelated PWJ (16.0 GT/s)	6041014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range. This test required PWJ clock pattern.
Tx, Total uncorrelated PWJ (2.5 GT/s)	4011014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range.
Tx, Total uncorrelated PWJ (32.0 GT/s)	5051014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range. This test required PWJ clock pattern.
Tx, Total uncorrelated PWJ (32.0 GT/s)	6051014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range. This test required PWJ clock pattern.
Tx, Total uncorrelated PWJ (5.0 GT/s)	4021014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range.
Tx, Total uncorrelated PWJ (5.0 GT/s)	5021014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range.
Tx, Total uncorrelated PWJ (5.0 GT/s)	6021014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range.
Tx, Total uncorrelated PWJ (64.0 GT/s)	6061014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range. This test required PWJ clock pattern.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Total uncorrelated PWJ (8.0 GT/s)	4031014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range.
Tx, Total uncorrelated PWJ (8.0 GT/s)	5031014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range.
Tx, Total uncorrelated PWJ (8.0 GT/s)	6031014	This test verifies that the maximum total uncorrelated PWJ TTX-UPW-TJ is within the allowed range.
Tx, Uncorrelated deterministic jitter (16.0 GT/s)	4041013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (16.0 GT/s)	5041013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (16.0 GT/s)	6041013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (2.5 GT/s)	4011013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (2.5 GT/s)	5011013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (2.5 GT/s)	6011013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (32.0 GT/s)	5051013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (32.0 GT/s)	6051013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (5.0 GT/s)	4021013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (5.0 GT/s)	5021013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (5.0 GT/s)	6021013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (64.0 GT/s)	6061013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (8.0 GT/s)	4031013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (8.0 GT/s)	5031013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated deterministic jitter (8.0 GT/s)	6031013	This test verifies that the maximum uncorrelated deterministic jitter TTX-UDJDD is within the allowed range.
Tx, Uncorrelated total jitter (16.0 GT/s)	4041012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Uncorrelated total jitter (16.0 GT/s)	5041012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (16.0 GT/s)	6041012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (2.5 GT/s)	4011012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (2.5 GT/s)	5011012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (2.5 GT/s)	6011012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (32.0 GT/s)	5051012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (32.0 GT/s)	6051012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (5.0 GT/s)	4021012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (5.0 GT/s)	5021012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (5.0 GT/s)	6021012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (64.0 GT/s)	6061012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (8.0 GT/s)	4031012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (8.0 GT/s)	5031012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Uncorrelated total jitter (8.0 GT/s)	6031012	This test verifies that the maximum uncorrelated total jitter TTX-UTJ is within the allowed range.
Tx, Unit interval (16.0 GT/s)	4041000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (16.0 GT/s)	5041000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (16.0 GT/s)	6041000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Tx, Unit interval (2.5 GT/s)	4011000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here.
Tx, Unit interval (2.5 GT/s)	5011000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (2.5 GT/s)	6011000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (32.0 GT/s)	5051000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (32.0 GT/s)	6051000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (5.0 GT/s)	4021000	A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The mean recovered TX UI is reported here.
Tx, Unit interval (5.0 GT/s)	5021000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (5.0 GT/s)	6021000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (64.0 GT/s)	6061000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (8.0 GT/s)	4031000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 4-19 of the PCI Express Base Specification.
Tx, Unit interval (8.0 GT/s)	5031000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.
Tx, Unit interval (8.0 GT/s)	6031000	The purpose of this test is to verify that the unit interval measured at the transmitter Tx is within the conformance limits specified in Table 8-6 of the PCI Express Base Specification.

3 Test Names and IDs

4 Instruments

The following table shows the instruments used by this application. The name is required by various remote interface methods.

- Instrument Name – The name to use as a parameter in remote interface commands.
- Description – The description of the instrument.

For example, if an application uses an oscilloscope and a pulse generator, then you would expect to see something like this in the table below:

Table 5 Example Instrument Information

Name	Description
scope	The primary oscilloscope.
Pulse	The pulse generator used for Gen 2 tests.

and you would be able to remotely control an instrument using:

ARSL syntax (replace [description] with actual parameter)

```
-----  
arsl -a ipaddress -c "SendScpiCommandCustom 'Command=[scpi  
command];Timeout=100;Instrument=pulsegen'"
```

```
arsl -a ipaddress -c "SendScpiQueryCustom 'Command=[scpi  
query];Timeout=100;Instrument=pulsegen'"
```

C# syntax (replace [description] with actual parameter)

```
-----  
SendScpiCommandOptions commandOptions = new SendScpiCommandOptions();  
commandOptions.Command = "[scpi command]";  
commandOptions.Instrument = "[instrument name]";  
commandOptions.Timeout = [timeout];  
remoteAte.SendScpiCommand(commandOptions);
```

```
SendScpiQueryOptions queryOptions = new SendScpiQueryOptions();  
queryOptions.Query = "[scpi query]";  
queryOptions.Instrument = "[instrument name]";
```

```
queryOptions.Timeout = [timeout];  
remoteAte.SendScpiQuery(queryOptions);
```

Here are the actual instrument names used by this application:

NOTE

The file, "InstrumentInfo.txt", which may be found in the same directory as this help file, contains all of the information found in the table below in a format suitable for parsing.

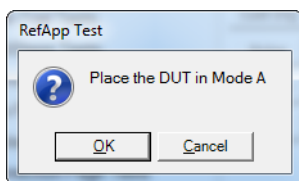
Table 6 Instrument Names

Instrument Name	Description
Infiniium	The primary oscilloscope
PFAGenerator	PFAGenerator

5 Message IDs

During the normal course of operation, an application displays multiple message prompts. The application's remote interface exposes a callback capability which enables remote clients to receive the text found in the prompt and to programmatically select the desired response (OK, Cancel, etc.). In order to determine which message is being received, the remote program could parse the message and look for key words. However, because message text is subject to change, a more reliable approach is to use the "message ID" that is attached to the more frequently-seen messages. The following table shows the IDs of the messages that this application may prompt during nominal operation.

For example, if the application may display the following prompt:



then you would expect to see something like this in the table below:

Message	ID	Responses	Usage
DUT mode message	313AEE2F-9EF0-476f-A2EB-29A5C7DE686F	OK=action completed and proceed, Cancel = abort test	App

- Message – A summary of the message in the prompt.
- ID – A unique code that will never change for this prompt, even if the message text changes (assuming the underlying purpose is maintained).
- Responses – The buttons on the prompt and their actions.
- Usage – The scope of the message:
 - "Common" – This message/ID may be used by other apps.

- "App" – This message/ID is unique to this app.
- "<testID>" – This message/ID is unique to this test ID.

A remote client would then structure the code in its message callback handler as shown below to manage message identification:

```
private static void OnSimpleMessage(object sender, MessageEventArgs e)
{
    if (e.ID == "313AEE2F-9EF0-476f-A2EB-29A5C7DE686F")
    {
        // Add code here to set the DUT in Mode A

        e.Response = DialogResult.OK;
    }
}
```

Here are actual message IDs used by this application:

NOTE

The file, "MessageInfo.txt", which may be found in the same directory as this help file, contains all of the information found in the table below in a format suitable for parsing.

Table 7 Message IDs

Message	ID	Responses	Usage
Acq Limit: Can't determine minimum bandwidth	25A86458-151E-413D-B890-FC30CFD5ECAA	OK	Instrument
Activating limit will conflict with existing results	31A39751-6019-41de-89DF-59DB239DF978	OK=delete conflicting results, Cancel=cancel activation	Instrument
Already running tests	022467B0-6E08-40eb-B4D4-BBB018FBFBC7	OK	Instrument
App startup aborted	C2B67F67-E5D5-4845-8B63-443781223010	OK	Instrument
Can't set memory depth	FFFF1129-BD83-4318-993E-64C94033CEC4	OK=skip step and continue, Cancel=abort test	Instrument
Channel Setup: Unknown scope channel	CDE944EB-F440-4CB1-AFDC-7596461BCD86	OK	Instrument
Compliance/Debug mode change	9C72A970-8D7D-4b37-9787-48AEEA5DC3F1	OK=change mode, Cancel=abort action	Instrument
Confirmation Required	37437505-160C-4cc8-BA06-093C12994C1E	OK=continue, Cancel=abort test	Instrument
Connection change	879629E6-78FA-4a87-B247-A9DB4F0D7330	Abort=abort run, Retry=connection changed - continue run, Ignore=connection not chagned - continue run	Instrument

Table 7 Message IDs (continued)

Message	ID	Responses	Usage
Debug pause (messages vary)	50B66A97-A6A9-413f-8329-76DFAC492FD6	OK=resume, Cancel=abort run	Instrument
End of run summary	602F9866-F975-42b7-842C-D8447E5E3FCB	OK	Instrument
End of run summary (test aborted)	124580E4-4486-42d4-B908-C6D0FB2AEE93	OK	Instrument
Error during CSV file generation	C88B1C64-8334-4b15-8727-81F5E2BA2ED4	OK	Instrument
Error during app exit	81112706-F720-4787-81D3-B22A9B692B41	OK	Instrument
Expected signal not found	86C74779-322E-4585-A07A-26A2C8FAAC84	Abort=abort test, Retry=retry failed action, Ignore=skip failed step	Instrument
Expected signal not found	7957D5B8-E62D-4224-A7DD-70361E816A43	Retry=retry failed action, Cancel=abort test	Instrument
InfiniiSim: Not available because scope default prevented	B8461A2C-9F5F-4AF3-94C1-DF77080D517A	OK	Instrument
InfiniiSim: Scope doesn't support settings found in project	C9BC2205-8041-448b-AF31-CF602183E989	OK	Instrument
InfiniiSim: Unknown scope channel	4E5ECAf6-867C-47B3-982D-5F07E2090703	OK	Instrument
Measurement Server no Measure Workers declared	54A8428D-8E22-4286-AC88-7495821ABA77	OK=retry, Cancel=abort run	Instrument
No test selected	B5D233AD-9EB4-4ac2-A443-A30A13643978	OK	Instrument
PrecisionProbe and InfiniiSim controllers turned off after config change	B4477006-D6D1-4375-9FF7-D8177FFC1BF9	OK	Instrument
PrecisionProbe/PrecisionCable: Not available because scope default prevented	6E60C9F8-8FBF-419C-B70A-B666FBDE3677	OK	Instrument
PrecisionProbe/PrecisionCable: Scope doesn't support settings found in project	2FC3B6FA-E28C-4700-9F46-4ABBA86A0D90	OK	Instrument
PrecisionProbe/PrecisionCable: Switch Controller is enabled	22F46DA8-89AE-4370-A57C-571DCF5BB87E	OK	Instrument
PrecisionProbe/PrecisionCable: Unknown scope channel	6788685B-9E88-47E6-BAE6-862F5BF3C9BA	OK	Instrument

Table 7 Message IDs (continued)

Message	ID	Responses	Usage
Project loaded as read-only (reason)	98C785F8-D24F-4758-A18D-1CCE61F25371	OK	Instrument
Project loaded with errors	58AD7A02-1E63-4d77-BC6C-6EF3E37AAD5B	OK	Instrument
Project not loaded	B2615E9C-5ED7-4db7-AEAF-2BC25C62B656	OK	Instrument
Project save failed (unauthorized access)	89DCC194-6254-4902-AE63-B7CCD12C8B2A	OK	Instrument
Run paused	FE2CF871-6D4A-4080-8FF9-770075590D9F	OK=resume, Cancel=abort run	Instrument
Setting change requires result deletion	8732A3AB-142C-47e5-86EA-DB737F415DDE	OK=delete results; Cancel=abort change	Instrument
Store mode change requires result deletion	884CDFDE-605E-4d04-B8FD-9B181E7FA468	OK=delete results, Cancel=abort change	Instrument
Switch Matrix controller turned off after config change	FC95EBAA-F33F-4eae-90BB-6A6A8F16E2DF	OK	Instrument
Switch Matrix: Auto mode unavailable after config change	6E5589DC-E073-4818-9E8A-782A75898475	OK	Instrument
Switch Matrix: Auto mode unavailable for model, all settings will be reset	F78BD2E2-BF29-42e0-98F8-23B6CE565B08	OK=go auto do reset, Cancel=abort action	Instrument
Switch Matrix: Confirm Auto mode	D5E1A12E-6218-4416-8451-5F9415D924BF	OK=go auto, Cancel=stay manual	Instrument
Switch Matrix: Obsolete items in settings discarded	0C45BD20-E0C2-481e-A3B6-9C1A26C2103A	OK	Instrument
Switch Matrix: Reconnect drivers	047FE44F-B251-49fa-B3C7-5590317230CD	Yes=use saved addresses, No=prompt for new addresses, Cancel=reset all settings	Instrument
Switch Matrix: Remove all InfiniiSim settings	C5560182-73BE-4901-941E-3DAEC9F07B33	OK=remove, Cancel=abort action	Instrument
Switch Matrix: User cancelled settings load	50F3FB70-AA6B-488e-8CFA-62CDA756F746	OK	Instrument
SwitchMatrix: Correction reset due to application route change	95FEA629-3BE1-4288-BA34-426516018B07	OK=Accept new routing, Cancel=Reset switch matrix settings	Instrument
SwitchMatrix: Instrument already connected to another driver	08556148-4D63-4edd-B894-22916F39849A	OK	Instrument

Table 7 Message IDs (continued)

Message	ID	Responses	Usage
SwitchMatrix: Max num drivers exceeded	7D8994AB-FCC2-4294-87B3-19B972BB6510	OK	Instrument
SwitchMatrix: Reset after drive reconnect fail	CF3E93B6-77FA-4FD7-B656-D286BE1C7C75	OK	Instrument
SwitchMatrix: Reset after drive reconnect fail	D298A4B8-F077-49BE-9CB2-AE6C14FB4705	OK	Instrument
SwitchMatrix: Unexpected multi-SPDT module	2723591D-55A9-44F3-9318-B732995D9427	OK	Instrument
SwitchMatrix: Unknown current switch state	ECE6535B-5C1A-4688-9E45-FB255435CC92	OK	Instrument
SwitchMatrix: Will reset due to requested change	420FCEA9-0FF4-4088-B47A-3189413EA0AD	OK=Allow the reset, Cancel=Abort the original requested change	Instrument
Unknown EEyeLocation parameter	FCA1C61B-D2EA-4671-AD48-9C080A6C6039	OK	Instrument
Upgrade app to open project	794C6148-ADF4-4b24-895D-74D94B76F8AE	OK	Instrument

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